U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

CLASSIFICATION ORDER 1898

OCTOBER 5, 2010

PROJECT E-6217

The following classification changes will be effected by this order:

	Class	**Subclass**	**Art Unit**	**Ex'r Search Room**
Abolished:	324	158.1, 750-772	2829	RND0000B15
Established:	324	750.01-750.09, 750.1, 750.11-750.19, 750.2, 750.21-750.29, 750.3, 754.01-754.09, 754.1, 754.11-754.19, 754.2, 754.21-754.29, 754.3, 754.31, 755.01-755.09, 755.1, 755.11, 756.01-756.07, 757.01-757.05, 758.01-758.05, 759.01-759.03, 760.01, 760.02, 761.01, 762.01-762.09, 762.1, 763.01, 763.02, 764.01, 765.01	2829	RND0000B15

The following classes are also impacted by this order:
33, 73, 257, 310, 349, 702, 977

This order includes the following:

A. CLASSIFICATION MANUAL CHANGES

B. LISTING OF PRINCIPAL SOURCE OF ESTABLISHED AND DISPOSITION OF ABOLISHED SUBCLASSES

C. CHANGES TO THE USPC-TO-IPC CONCORDANCE

D. DEFINITION CHANGES AND NEW OR ADDITIONAL DEFINITIONS

CLASSIFICATION ORDER 1898

October 5, 2010

PROJECT E6217

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300 **PARTICLE PRECESSION RESONANCE**
301 .Using a magnetometer
302 ..To determine direction
303 .Using well logging device
304 .Using optical pumping or sensing device
305 ..Having particular optical cell structure
306 .Determine fluid flow rate
307 .Using a nuclear resonance spectrometer system
308 ..Including a test sample and control sample
309 ..To obtain localized resonance within a sample
310 ..By scanning sample frequency spectrum
311 ..With signal decoupling
312 ..By spectrum storage and analysis
313 ..Including polarizing magnetic field/radio frequency tuning
314 ..With conditioning of transmitter signal
315 ..With sample resonant frequency and temperature interdependence
316 .Using an electron resonance spectrometer system
317 ..Including a test sample and control sample
318 .Spectrometer components
319 ..Polarizing field magnet
320 ...With homogeneity control
321 ..Sample holder structure
322 ..Electronic circuit elements
323 **OF GEOPHYSICAL SURFACE OR SUBSURFACE IN SITU**
324 .Including borehole fluid investigation
325 ..To determine fluid entry
326 .For small object detection or location
327 ..Using oscillator coupled search head
328 ...Of the beat frequency type
329 ..Using movable transmitter and receiver
330 .By aerial survey
331 ..For magnetic field detection
332 .With radiant energy or nonconductive-type transmitter
333 ..Within a borehole
334 ..With separate pickup
335 ...Employing multiple frequencies
336 ...To detect transient signals
337 ...To detect return wave signals
338 ...Within a borehole
339 ....By induction logging
340 .....To measure susceptibility
341 .....To measure dielectric constant
342 .....Using a toroidal coil
343 .....Using angularly spaced coils
344 .With radiant energy or nonconductive-type receiver
345 .By magnetic means
346 ..Within a borehole
347 .Using electrode arrays, circuits, structure, or supports
348 ..For detecting naturally occurring fields, currents, or potentials
349 ...Of the telluric type
350 ....Including magneto-telluric type
351 ...Within a borehole
352 ....Combined with artificial source measurement
353 ....With fluid movement or pressure variation
354 ..Coupled to artificial current source
355 ...Within a borehole
356 ....While drilling
357 ...Including separate pickup of generated fields or potentials
358 ....With three electrodes
359 ....With nonelectrode pickup means
360 ....Using a pulse-type current source
361 .....With mechanical current reversing means
362 .....To measure induced polarization
363 ....By varying the path of current flow
364 .....Using frequency variation
365 ....Offshore
366 ....For well logging
367 .....Using a pad member
368 .....Cased borehole
369 .....While drilling

436 ..Including oscillator in measurement circuit
437 ..Including probe structure
438 .Using a pH determining device
439 .Using a conductivity determining device
440 ..Which includes a dropping mercury cell
441 ..Which includes a temperature responsive element
442 ..Which includes an oscillator
443 ..Having a bridge circuit
444 ..Which includes current and voltage electrodes
445 ..Having inductance probe structure
446 ..Having conductance probe structure
447 ...With movable or adjustable electrode
448 ...With concentric electrodes
449 ...With axially arranged electrodes
450 ..Which includes particular cell container structure
451 **A MATERIAL PROPERTY USING THERMOELECTRIC PHENOMENON**
452 **A MATERIAL PROPERTY USING ELECTROSTATIC PHENOMENON**
453 .In a liquid
454 .Frictionally induced
455 .Corona induced
456 .For flaw detection
457 **ELECTROSTATIC FIELD**
458 .Using modulation-type electrometer
459 **USING IONIZATION EFFECTS**
460 .For monitoring pressure
461 ..Using a radioactive substance
462 ..Using thermionic emissions
463 ..Using a magnetic field
464 .For analysis of gas, vapor, or particles of matter
465 ..Using electronegative gas sensor
466 ..Using a filter
467 ..Using test material desorption
468 ..Using thermal ionization
469 ..Using a radioactive substance
470 ..Using thermionic emission
200 **MAGNETIC**
201 .Susceptibility
202 .Calibration
203 .Curie point determination
204 .Fluid material examination
205 .Permanent magnet testing
206 .Movable random length material measurement
207.11 .Displacement
207.12 ..Compensation for measurement
207.13 ..Having particular sensor means
207.14 ...Diverse sensors
207.15 ...Inductive
207.16 ....Electrically energized
207.17 .....Separate pick-up
207.18 .....Differential type (e.g., LVDT)
207.19 .....Differential bridge circuit
207.2 ...Hall effect
207.21 ...Magnetoresistive
207.22 ..Having particular sensed object
207.23 ..Plural measurements (e.g., linear and rotary)
207.24 ..Linear
207.25 ..Rotary
207.26 ..Approach or retreat
209 .Stress in material measurement
210 .Magnetic information storage element testing
211 ..Memory core storage element testing
212 ..Dynamic information element testing
213 .Magnetic recording medium on magnetized object records object field
214 .By paramagnetic particles
215 ..With pattern enhancing additive
216 ..Flaw testing
217 .Railroad rail flaw testing
218 ..Rail joint cutout
219 .Magnetic sensor within material
220 ..Sensor supported, positioned, or moved within pipe
221 ...Borehole pipe testing
222 .Hysteresis or eddy current loss testing
223 .Hysteresis loop curve display or recording
224 .With temperature control of material or element of test circuit
225 .With compensation for test variable
226 .Combined
227 .Plural tests
228 .With means to create magnetic field to test material

750.04 ....Thermal matching of guidance member
750.05 ....Burn-in
750.06 .....With temperature sensing
750.07 ......With feedback control
750.08 ....By fluid
750.09 ....By heat sink
750.1 .....With biasing means
750.11 ....Thermoelectric
750.12 ....Electromagnetic
750.13 ....Of test device transporting means
750.14 ..Environmental control
750.15 ..With identification on device under test (DUT)
750.16 ..Relative positioning or alignment of device under test and test structure
750.17 ...By capacitive means
750.18 ...By information on device under test
750.19 ...Adjustable support for device under test
750.2 ....Vacuum support
750.21 ....Magnetic support
750.22 ...Testing device mounted for multi-directional movement
750.23 ...Using optical means
750.24 ...By electrical contact means
750.25 ...By mechanical means
750.26 ..Shielding or casing of device under test or of test structure
750.27 ...EMI interference
750.28 ...Temperature effect
750.29 ...Mechanical effect
750.3 ..Built-in test circuit
754.01 ..Test probe techniques
754.02 ...Hand-held
754.03 ...Contact probe
754.04 ....Liquid state
754.05 ....Kelvin probe
754.06 ....Waveguide probe
754.07 ....Probe or probe card with build-in circuit element
754.08 ....In or on support for device under test
754.09 .....Carrier feature
754.1 ....Probe contact confirmation
754.11 ....Probe contact enhancement or compensation
754.12 ....Biasing means
754.13 .....Mechanical
754.14 .....Spring
754.15 .....Fluid pressure
754.16 ......Chamber or bladder
754.17 .....Magnetic means
754.18 ....With interpose
754.19 ....With recording of test result
754.2 ....Penetrative
754.21 ...Non-contact probe
754.22 ....Electron beam
754.23 ....Optical beam
754.24 ....With plasma probe
754.25 ....Ultrasonic
754.26 ....Tunnel current probe
754.27 ....Electrical field
754.28 .....Capacitive coupling
754.29 ....Magnetic field
754.3 ....Intermolecular
754.31 ....Radio wave
755.01 ..Probe structure
755.02 ...Coaxial
755.03 ...Rigid
755.04 ...Force absorption
755.05 ....Spring
755.06 ....Buckling
755.07 ...Cantilever
755.08 ...Elastomeric
755.09 ...Membrane
755.1 ...Dendritic structure
755.11 ...Elongated pin or probe
756.01 ..Support for device under test or test structure
756.02 ...DUT socket or carrier
756.03 ...Probe card
756.04 ...Pin fixture
756.05 ...With electrical connectors
756.06 ...With impedance matching
756.07 ...Board or plate
757.01 ..Transporting or conveying the device under test to the testing station
757.02 ...Printed circuit board
757.03 ...Wafer
757.04 ...Packaged IC or unpackaged die or dice
757.05 ...Multiple chip module
758.01 ..Cleaning probe or device under test
758.02 ...By laser ablation
758.03 ...By blowing air
758.04 ...By scraping
758.05 ...By chemical means
759.01 ..After-test activity
759.02 ...Marking tested objects
759.03 ...Sorting tested objects
760.01 ..Test of liquid crystal device

760.02 ...Thin film transistor type (TFT)
761.01 ..Test of solar cell
762.01 ..Test of semiconductor device
762.02 ...Packaged integrated circuits
762.03 ...Integrated circuit die
762.04 ....TAB carrier
762.05 ...Semiconductor wafer
762.06 ...Multiple chip module
762.07 ...Diode
762.08 ...Bipolar transistor
762.09 ...Field effect transistor
762.1 ...With barrier layer
763.01 ..Printed circuit board
763.02 ...Both sides
764.01 ..Power supply
765.01 ..Motor or generator fault
538 ..Electrical connectors
539 ..Multiconductor cable
540 ...With sequencer
541 ...For insulation fault
542 ...Having a light or sound indicator
543 ..Single conductor cable
544 ...For insulation fault
545 ..Armature or rotor
546 ..Winding or coil
547 ...Transformer
548 ..Capacitor
549 ..Resistor
550 ..Fuse
551 ..Insulation
552 ...Bushing
553 ...Oil
554 ...Sheet material
555 .Instruments and devices for fault testing
556 ..Having a lamp or light indicator
557 **FOR INSULATION FAULT OF NONCIRCUIT ELEMENTS**
558 .Where element moves while under test
559 .Where a moving sensing electrode scans a stationary element under test
600 **IMPEDANCE, ADMITTANCE OR OTHER QUANTITIES REPRESENTATIVE OF ELECTRICAL STIMULUS/RESPONSE RELATIONSHIPS**
601 .Calibration
602 .With auxiliary means to condition stimulus/response signals
603 ..For excitation
604 ...Including marker signal generator circuit
605 ..For response signal evaluation or processing
606 ...Including a signal comparison circuit
607 ...Including a conversion (e.g., A->D or D-> A) process
608 ...Including a ratiometric function
609 ..For sensing
610 ...Including a bridge circuit
611 ...Including a remote type circuit
612 .Parameter related to the reproduction or fidelity of a signal affected by a circuit under test
613 ..Noise
614 ...Signal to noise ratio or noise figure
615 ..Transfer function type characteristics
616 ...Gain or attenuation
617 ...Response time or phase delay
618 ...Transient response or transient recovery time (e.g., damping)
619 ...Selective type characteristics
620 ..Distortion
621 ...Envelope delay
622 ...Phase
623 ...Harmonic
624 ...Intermodulation
625 ...Dissymmetry or asymmetry
626 ...Nonlinearity
627 ..Shielding effectiveness (SE)
628 ...Circuit interference (e.g., crosstalk) measurement
629 .Distributive type parameters
630 ..Plural diverse parameters
631 ..Using wave polarization (e.g., field rotation)
632 ..Using particular field coupling type (e.g., fringing field)
633 ..Using resonant frequency
634 ...To determine water content
635 ...To determine dimension (e.g., distance or thickness)
636 ...With a resonant cavity
637 ..Using transmitted or reflected microwaves

638 ...Scattering type parameters (e.g., complex reflection coefficient)
639 ...Where energy is transmitted through a test substance
640 ....To determine water content
641 ....To determine insertion loss
642 ...Where energy is reflected (e.g., reflectometry)
643 ....To determine water content
644 ....To determine dimension (e.g., distance or thickness)
645 ....Having standing wave pattern
646 ....To determine reflection coefficient
647 ..Using a comparison or difference circuit
648 ...With a bridge circuit
649 .Lumped type parameters
650 ..Using phasor or vector analysis
651 ...With a bridge circuit
652 ..Of a resonant circuit
653 ..For figure of merit or Q value
654 ..Using inductive type measurement
655 ...Including a tuned or resonant circuit
656 ...Including a comparison or difference circuit
657 ....Using a bridge circuit
658 ..Using capacitive type measurement
659 ...With loss characteristic evaluation
660 ...With variable electrode area
661 ...With variable distance between capacitor electrodes
662 ....To determine dimension (e.g., thickness or distance)
663 ...Where a material or object forms part of the dielectric being measured
664 ....To determine water content
665 .....By comparison or difference circuit
666 ......Including a bridge circuit
667 .....By frequency signal response, change or processing circuit
668 ......Including a tuned or resonant circuit
669 .....With compensation means
670 ......For temperature variations
671 ....To determine dimension (e.g., dielectric thickness)
672 ....By comparison or difference circuit
673 .....Including a bridge circuit
674 ....By frequency signal response, change or processing circuit
675 .....Including a tuned or resonant circuit
676 ...With pulse signal processing circuit
677 ....Including R/C time constant circuit
678 ....Including charge or discharge cycle circuit
679 ...With comparison or difference circuit
680 ....Including a bridge circuit
681 ...With frequency signal response, change or processing circuit
682 ....Including a tuned or resonant circuit
683 ...With phase signal processing circuit
684 ...With compensation means
685 ....For temperature variation
686 ...With a capacitive sensing means
687 ....Having fringing field coupling
688 ....Including a guard or ground electrode
689 ....To determine water content
690 ....Including a probe type structure
691 ..Using resistance or conductance measurement
692 ...With living organism condition determination using conductivity effects
693 ...With object or substance characteristic determination using conductivity effects
694 ....To determine water content
695 .....Where the object moves while under test
696 .....With a probe structure
697 ....For interface
698 ....To determine oil qualities
699 ....To determine dimension (e.g., distance or thickness)
700 .....Including corrosion or erosion
701 ....Where the object moves while under test
702 ...With radiant energy effects

703 ....Including heating
704 ...With ratio determination
705 ...With comparison or difference circuit
706 ....Including a bridge circuit
707 ...With frequency response, change or processing circuit
708 ....Including a tuned or resonant circuit
709 ...With phase signal processing circuit
710 ...With pulse signal processing circuit
711 ....Including R/C time constant circuit
712 ....Including a digital or logic circuit
713 ...With voltage or current signal evaluation
714 ....Including a potentiometer
715 ....Including a particular probing technique (e.g., four point probe)
716 .....To determine dimension (e.g., distance or thickness)
717 .....To determine material composition
718 .....To detect a flaw or defect
719 ...With semiconductor or IC materials quality determination using conductivity effects
720 ...With compensation means
721 ....For temperature variation
722 ...Device or apparatus determines conductivity effects
723 ....Potentiometer
724 ....Using a probe type structure
725 .Using a particular bridge circuit
726 .Transformer testing (e.g., ratio)
727 .Piezoelectric crystal testing (e.g., frequency, resistance)

66 **CONDUCTOR IDENTIFICATION OR LOCATION (E.G., PHASE IDENTIFICATION)**

67 .Inaccessible (at test point) conductor (e.g., buried in wall)

160 **ELECTRICAL SPEED MEASURING**

161 .Speed comparing means
162 .With acceleration measuring means
163 .Including speed analog electrical signal generator
164 ..Eddy current generator type (e.g., tachometer)
165 ..With direction indicator
166 .Including speed-related frequency generator
167 ..Including rotating magnetic field actuated indicator
168 ..Including periodic switch
169 ...In ignition system
170 ....High voltage speed signal type
171 ...With extent-of-travel indicator
172 ..Including synchronized recording medium
173 ..Including magnetic detector
174 ...Permanent magnet type
175 ..Including radiant energy detector
176 .Including object displacement varied variable circuit impedance
177 .Including motor current or voltage sensor
178 .Including "event" sensing means
179 ..Magnetic field sensor
180 ..Mechanically actuated switch

71.1 **DETERMINING NONELECTRIC PROPERTIES BY MEASURING ELECTRIC PROPERTIES**

71.2 .Erosion
71.3 .Beam of atomic particles
71.4 .Particle counting
71.5 .Semiconductors for nonelectrical property
71.6 .Superconductors

72 **TESTING POTENTIAL IN SPECIFIC ENVIRONMENT (E.G., LIGHTNING STROKE)**

72.5 .Voltage probe

73.1 **PLURAL, AUTOMATICALLY SEQUENTIAL TESTS**

74 **TESTING AND CALIBRATING ELECTRIC METERS (E.G., WATT-HOUR METERS)**

75 .By stroboscopic means

76.11 **MEASURING, TESTING, OR SENSING ELECTRICITY, PER SE**

76.12 .Analysis of complex waves
76.13 ..Amplitude distribution
76.14 ...Radiometer (e.g., microwave, etc.)
76.15 ...With sampler

76.16 ...With counter
76.17 ...With integrator
76.18 ...With slope detector
76.19 ..Frequency spectrum analyzer
76.21 ...By Fourier analysis
76.22 ...Real-time spectrum analyzer
76.23 ...With mixer
76.24 ...With sampler
76.25 ...With slope detector
76.26 ...Scanning-panoramic receiver
76.27 ....With particular sweep circuit
77.11 ...Nonscanning
76.28 ....Digital filter
76.29 ....With filtering
76.31 .....Parallel filters
76.32 .....With space discharge device
76.33 ....Correlation
76.34 .....With space discharge device
76.35 ....With delay line
76.36 ....With optics
76.37 .....Bragg cell
76.38 ..With sampler
76.39 .Frequency of cyclic current or voltage (e.g., cyclic counting etc.)
76.41 ..Frequency comparison, (e.g., heterodyne, etc.)
76.42 ...With sampler
76.43 ...With plural mixers
76.44 ...With filtering
76.45 ....Bandpass
76.46 ....Plural
76.47 ...Digital output
76.48 ....With counter
76.49 ..Tuned mechanical resonator (e.g., reed, piezocrystal, etc.)
76.51 ..By tuning (e.g., to resonance,etc.)
76.52 ..By phase comparison
76.53 ...With phase lock
76.54 ...With delay line
76.55 ...Digital output
76.56 ....With microwave frequency detection
76.57 ....With tone detection
76.58 ....With sampler
76.59 ....With multiplexing
76.61 ....With memory
76.62 ....With counter
76.63 .....Using register
76.64 .....Plural
76.65 ....With space discharge device
76.66 ...With capacitive energy storage
76.67 ....With space discharge device
76.68 ...With filtering
76.69 ...Current output proportional to frequency
76.71 ...Nulling circuit
76.72 ...Qualitative output
76.73 ...With saturable device
76.74 ...Deviation measurement
76.75 ..Having inductive sensing
76.76 ..With space discharge device
76.77 .Phase comparison (e.g., between cyclic pulse voltage and sinusoidal current, etc.)
76.78 ..Quadrature sensing
76.79 ..Feedback control, electrical
76.81 ..Feedback control, mechanical
76.82 ..Digital output
76.83 ..Analog output
84 ..With waveguide (e.g., coaxial cable)
85 ..With frequency conversion
86 ..Polyphase (e.g., phase angle, phase rotation or sequence)
87 ..With nonlinear device (e.g., saturable reactor, rectifier), discharge device (e.g., gas tube) or lamp
88 ...Cathode ray
89 ...Space discharge control means (e.g., grid)
90 ..Electrodynamometer instrument
91 ..Synchroscope type
92 .Fluid (e.g., thermal expansion)
93 ..Conductive field (e.g., mercury)
94 ...Electrolytic
95 .With waveguide or long line
96 .Using radiant energy
97 ..Light beam type (e.g., mirror galvanometer, parallax-free scale)
98 .Balancing (e.g., known/unknown voltage comparison, bridge, rebalancing)
99 R ..Automatic
100 ...With recording
99 D ...Digital voltmeters
101 .Non-rebalancing bridge
102 .Transient or portion of cyclic
103 R .Demand, excess, maximum or minimum (e.g., separate meters for positive and negative power, peak voltmeter)
104 ..Thermal (e.g., actuation)
103 P ..Peak voltmeters

105 .Thermal (e.g., compensation)
106 ..Actuation
107 .Polyphase
108 ..Positive, negative or zero sequence
109 .Electrostatic attraction or piezoelectric
110 .Meter protection or fraud combatting
111 .With storage means for voltage or current (e.g., condenser banks)
112 ..Tape, sheet (e.g., disk) or wire (e.g., magnetic) storage
113 .Recording
114 .Plural meters (e.g., plural movements in one case)
115 .Plural ranges, scales or registration rates
116 ..With register (e.g., discount type, demand penalty)
117 R .Magnetic saturation (e.g., in field or in amplifier)
117 H ..Hall effect
118 .Modulator/demodulator
119 .With rectifier (e.g., A.C. to D.C.)
120 .With voltage or current conversion (e.g., D.C. to A.C., 60 to 1000)
121 R .Cathode ray (e.g., magic eye)
121 E ..Magic eye indicators
122 .Gaseous discharge (e.g., spark gap voltmeter)
123 R .With amplifier or space discharge device
124 ..Inverted amplifier
123 C ..Feedback amplifiers
125 .Inertia control, instrument damping and vibration damping
126 .With coupling means (e.g., attenuator, shunt)
127 ..Transformer (e.g., split core admits conductor carrying unknown current)
128 ..Selective filter
129 .Polepiece (e.g., split) admits nonunitary input conductor
130 .Self-calibration
131 .Suppressed zero
132 .Nonlinear (e.g., Thyrite)
133 .Nonquantitative (e.g., hot-line indicator, polarity tester)
134 .With commutator or reversing or pulsating switch (e.g., D.C. watt-hour meter)
135 ..Oscillating
136 .With rolling wheel or ball (e.g., transmission, integrating)
137 .Eddy current rotor (e.g., A.C. integrating wattmeter)
138 ..With phase adjustment
139 .Motor-driven, time-controlled or oscillating (e.g., ratchet)
140 R .Plural inputs (e.g., summation, ratio)
141 ..Voltamperes (real or reactive)
142 ..Watts
140 D ..Ratio
143 .Plural active motor elements (e.g., for two crossed pointers)
144 .With electromagnetic field (e.g., dynamometer)
145 ..Solenoid plunger type
146 ..With permanent magnet (e.g., field, vane)
147 ..Soft iron vane
149 .With probe, prod or terminals
150 .Eccentrically pivoted coil
151 R .With permanent magnet
152 ..Drag magnet
151 A ..Permanent magnet core
153 .With register
154 R .With rotor (e.g., filar suspension, zero set, balancing)
155 ..With pivot (e.g., internal friction compensation, anticreep)
154 PB ..Pointer and bearing details
156 .Casings
157 .Combined

CROSS-REFERENCE ART COLLECTIONS

800 **DIVINING RODS**

FOREIGN ART COLLECTIONS

FOR 000 **CLASS-RELATED FOREIGN DOCUMENTS**

Any foreign patents or non-patent literature from subclasses that have been reclassified have been transferred directly to FOR Collections listed below. These Collections contain ONLY foreign patents or non-patent literature. The parenthetical references in the Collection titles refer to the abolished subclasses from which these Collections were derived.

FAULT DETECTING IN ELECTRIC CIRCUITS AND OF ELECTRIC COMPONENTS(324/500)

.Of individual circuit component or element(324/537)

FOR 100 ..System sensing fields adjacent device under test (DUT) (324/750)

FOR 101 ...Using electron beam probe (324/751)

FOR 102 ...Using light probe (324/752)

FOR 103 ...Using electro-optic device (324/753)

OF GEOPHYSICAL SURFACE OR SUBSURFACE IN SITU (324/323)

.Using electrode arrays, circuits, structure, or supports (324/347)

FOR 104 ..With probe elements (324/754)

FOR 105 ...Internal of or on support for device under test (DUT): (324/755)

FOR 106 ...Contact confirmation (324/756)

FOR 107 ...Probe contact enhancement (324/757)

FOR 108 ...Probe alignment or positioning (324/758)

FOR 109 ...With recording of test results on DUT (324/759)

FOR 110 ...With temperature control (324/760)

FOR 111 ...Pin (324/761)

FOR 112 ...Cantilever (324/762)

FOR 113 ..DUT including test circuit (324/763)

FOR 114 ..With identification of DUT (324/764)

FOR 115 ..Test of semiconductor device (324/765)

FOR 116 ...With barrier layer (324/766)

FOR 117 ....Diode (324/767)

FOR 118 ....Bipolar transistor (324/768)

FOR 119 ....Field effect transistor (324/769)

FOR 120 ..Liquid crystal device test (324/770)

FOR 121 ..Power supply test (324/771)

FOR 122 ..Motor or generator fault tests (324/772)

FOR 123 **MISCELLANEOUS (324/158.1)**

OCTOBER 5, 2010

PROJECT E-6217

SOURCE CLASSIFICATION(S) OF PATENTS
IN NEWLY ESTABLISHED SUBCLASSES REPORT

Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
200/1 V	1	324/771	90
204/228.7	1	324/158.1	1119
205/791	1	324/158.1	1119
242/357	1	324/772	300
250/338.4	1	324/158.1	1119
250/370.11	1	324/752	156
250/393	1	324/766	95
257/461	1	324/767	184
257/48	1	324/757	142
	1	324/760	449
	1	324/765	1552
	2	324/158.1	1119
257/682	1	324/158.1	1119
257/686	1	324/763	517
29/593	1	324/754	1675
29/732	1	324/772	300
29/755	1	324/754	1675
29/759	1	324/158.1	1119
29/828	1	324/754	1675
29/846	2	324/754	1675
29/874	1	324/158.1	1119
	2	324/754	1675
	2	324/758	419
29/884	1	324/755	479
	2	324/754	1675
307/125	1	324/158.1	1119
307/31	1	324/158.1	1119
307/64	1	324/771	90
310/361	1	324/765	1552
310/419	1	324/772	300
318/146	1	324/772	300
318/400.01	1	324/772	300
318/433	1	324/772	300
318/490	1	324/772	300
318/798	1	324/772	300
323/265	1	324/771	90
323/266	1	324/769	169
323/268	1	324/765	1552
323/273	1	324/158.1	1119
323/282	1	324/765	1552
323/290	1	324/158.1	1119
324/105	1	324/158.1	1119
	1	324/765	1552

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SOURCE CLASSIFICATION(S) OF PATENTS
IN NEWLY ESTABLISHED SUBCLASSES REPORT

Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
324/107	1	324/772	300
324/108	1	324/772	300
324/113	1	324/772	300
324/115	1	324/772	300
	2	324/158.1	1119
324/117 H	1	324/765	1552
	2	324/158.1	1119
324/117 R	1	324/754	1675
	1	324/772	300
324/119	1	324/158.1	1119
324/120	1	324/769	169
324/123 R	1	324/158.1	1119
	1	324/765	1552
324/126	1	324/772	300
	2	324/158.1	1119
	3	324/765	1552
324/127	1	324/771	90
324/130	1	324/158.1	1119
324/132	1	324/769	169
324/133	1	324/158.1	1119
324/134	1	324/772	300
324/139	1	324/772	300
324/142	1	324/760	449
	2	324/158.1	1119
324/207.13	1	324/750	130
324/207.25	1	324/772	300
324/217	1	324/772	300
324/230	1	324/765	1552
324/238	1	324/752	156
324/240	1	324/765	1552
324/244	1	324/772	300
324/244.1	1	324/158.1	1119
	1	324/753	72
324/248	1	324/158.1	1119
324/258	1	324/772	300
324/301	1	324/765	1552
324/378	1	324/772	300
324/380	2	324/772	300
324/388	1	324/772	300
324/389	1	324/772	300
324/391	1	324/754	1675
324/402	1	324/772	300
324/411	1	324/751	215

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SOURCE CLASSIFICATION(S) OF PATENTS
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New Classification	Number of ORs	Source Classification	Number of ORs
324/415	1	324/158.1	1119
324/418	1	324/772	300
324/426	1	324/772	300
324/429	1	324/771	90
324/431	1	324/771	90
324/457	1	324/757	142
324/468	1	324/750	130
324/502	1	324/772	300
324/503	1	324/763	517
324/525	1	324/158.1	1119
	1	324/771	90
324/527	1	324/158.1	1119
	1	324/763	517
324/537	1	324/750	130
	1	324/753	72
	1	324/763	517
	1	324/767	184
	1	324/770	234
	1	324/771	90
	3	324/766	95
	4	324/765	1552
	11	324/158.1	1119
324/538	1	324/755	479
	3	324/158.1	1119
324/545	12	324/772	300
324/546	1	324/756	53
	2	324/772	300
324/547	1	324/772	300
324/548	1	324/158.1	1119
	1	324/765	1552
324/549	1	324/767	184
324/550	1	324/158.1	1119
	1	324/765	1552
	2	324/771	90
324/551	1	324/756	53
	1	324/772	300
324/555	1	324/158.1	1119
324/600	1	324/158.1	1119
324/601	1	324/158.1	1119
	1	324/762	181
324/613	1	324/763	517
324/616	1	324/158.1	1119
324/642	1	324/766	95

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
324/650	1	324/765	1552
324/656	1	324/158.1	1119
324/658	1	324/158.1	1119
	2	324/765	1552
324/66	1	324/158.1	1119
	1	324/768	75
324/663	1	324/765	1552
324/671	1	324/765	1552
324/678	1	324/765	1552
324/686	1	324/758	419
324/690	1	324/765	1552
324/693	1	324/158.1	1119
	1	324/765	1552
	1	324/766	95
324/698	1	324/158.1	1119
324/699	1	324/754	1675
	1	324/765	1552
324/702	2	324/158.1	1119
324/71.1	1	324/158.1	1119
	1	324/761	338
324/71.3	1	324/158.1	1119
324/71.5	1	324/752	156
324/713	1	324/158.1	1119
324/719	1	324/750	130
	1	324/754	1675
	3	324/765	1552
324/724	1	324/750	130
	1	324/754	1675
324/750.01	1	324/750	130
	1	324/750	130
	1	324/754	1675
	1	324/757	142
	1	324/758	419
	1	324/763	517
	1	324/769	169
	1	324/770	234
	2	324/751	215
	2	324/756	53
	2	324/760	449
	2	324/761	338
	2	324/769	169
	3	324/760	449
	3	324/765	1552

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New Classification	Number of ORs	Source Classification	Number of ORs
	3	324/772	300
	4	324/754	1675
	4	324/758	419
	4	324/763	517
	5	324/158.1	1119
	25	324/765	1552
	34	324/158.1	1119
324/750.02	1	324/750	130
	1	324/753	72
	1	324/754	1675
	1	324/755	479
	1	324/756	53
	1	324/760	449
	1	324/760	449
	1	324/761	338
	1	324/762	181
	1	324/763	517
	1	324/766	95
	1	324/770	234
	2	324/758	419
	2	324/765	1552
	2	324/767	184
	2	324/768	75
	2	324/769	169
	2	324/772	300
	3	324/750	130
	4	324/751	215
	5	324/158.1	1119
	5	324/755	479
	7	324/763	517
	9	324/758	419
	13	324/754	1675
	21	324/765	1552
	43	324/158.1	1119
324/750.03	1	324/750	130
	1	324/750	130
	1	324/752	156
	1	324/757	142
	1	324/768	75
	1	324/768	75
	1	324/772	300
	2	324/751	215
	2	324/762	181

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New Classification	Number of ORs	Source Classification	Number of ORs
	2	324/763	517
	2	324/770	234
	4	324/158.1	1119
	4	324/767	184
	5	324/752	156
	5	324/754	1675
	5	324/760	449
	5	324/765	1552
	5	324/766	95
	6	324/758	419
	7	324/769	169
	8	324/755	479
	23	324/158.1	1119
	25	324/754	1675
	51	324/765	1552
	79	324/760	449
324/750.04	1	324/158.1	1119
	1	324/158.1	1119
	1	324/754	1675
	1	324/758	419
	1	324/760	449
	3	324/760	449
324/750.05	1	324/752	156
	1	324/756	53
	1	324/762	181
	1	324/766	95
	1	324/767	184
	2	324/750	130
	2	324/763	517
	2	324/770	234
	3	324/754	1675
	3	324/767	184
	5	324/761	338
	6	324/158.1	1119
	7	324/757	142
	7	324/765	1552
	8	324/758	419
	14	324/760	449
	15	324/763	517
	24	324/158.1	1119
	24	324/754	1675
	27	324/755	479
	69	324/765	1552

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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	112	324/760	449
324/750.06	1	324/755	479
	1	324/769	169
	2	324/158.1	1119
	3	324/765	1552
	8	324/760	449
	12	324/760	449
324/750.07	1	324/750	130
	1	324/753	72
	1	324/769	169
	2	324/754	1675
	2	324/758	419
	2	324/765	1552
	6	324/158.1	1119
	29	324/760	449
324/750.08	1	324/752	156
	1	324/755	479
	1	324/761	338
	1	324/763	517
	1	324/765	1552
	1	324/767	184
	6	324/760	449
	7	324/765	1552
	8	324/754	1675
	9	324/158.1	1119
	58	324/760	449
324/750.09	1	324/158.1	1119
	1	324/755	479
	1	324/756	53
	1	324/765	1552
	2	324/158.1	1119
	2	324/755	479
	2	324/762	181
	2	324/767	184
	5	324/754	1675
	6	324/765	1552
	12	324/760	449
	31	324/760	449
324/750.1	1	324/760	449
	2	324/754	1675
	2	324/755	479
	2	324/765	1552
	3	324/760	449

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New Classification	Number of ORs	Source Classification	Number of ORs
324/750.11	1	324/158.1	1119
	1	324/750	130
	1	324/753	72
	1	324/754	1675
	1	324/756	53
	1	324/757	142
	1	324/763	517
	1	324/770	234
	2	324/760	449
	3	324/761	338
	5	324/765	1552
	6	324/760	449
324/750.12	1	324/751	215
	1	324/760	449
	1	324/765	1552
	1	324/770	234
324/750.13	1	324/755	479
	1	324/758	419
	1	324/761	338
	2	324/760	449
	3	324/754	1675
	4	324/760	449
	5	324/158.1	1119
324/750.14	1	324/761	338
	1	324/763	517
	1	324/771	90
	2	324/755	479
	2	324/758	419
	2	324/765	1552
	4	324/750	130
	6	324/751	215
	7	324/765	1552
	9	324/752	156
	10	324/158.1	1119
	11	324/760	449
	19	324/754	1675
324/750.15	1	324/750	130
	1	324/753	72
	1	324/761	338
	1	324/765	1552
	1	324/766	95
	4	324/763	517
	6	324/158.1	1119

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New Classification	Number of ORs	Source Classification	Number of ORs
	7	324/764	20
	7	324/765	1552
324/750.16	1	324/752	156
	1	324/759	15
	1	324/761	338
	1	324/765	1552
	1	324/769	169
	1	324/772	300
	2	324/753	72
	2	324/757	142
	2	324/763	517
	2	324/770	234
	3	324/750	130
	3	324/751	215
	4	324/158.1	1119
	4	324/761	338
	4	324/762	181
	7	324/754	1675
	7	324/755	479
	7	324/758	419
	8	324/158.1	1119
	11	324/765	1552
	19	324/758	419
	30	324/754	1675
324/750.17	1	324/757	142
	2	324/754	1675
	2	324/758	419
	2	324/765	1552
324/750.18	1	324/751	215
	1	324/755	479
	1	324/755	479
	1	324/756	53
	1	324/760	449
	3	324/765	1552
	5	324/158.1	1119
	7	324/754	1675
	9	324/758	419
324/750.19	1	324/753	72
	1	324/760	449
	1	324/761	338
	1	324/762	181
	1	324/763	517
	1	324/767	184

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New Classification	Number of ORs	Source Classification	Number of ORs
	1	324/770	234
	2	324/750	130
	2	324/752	156
	2	324/754	1675
	3	324/756	53
	3	324/759	15
	4	324/757	142
	4	324/761	338
	6	324/751	215
	6	324/758	419
	7	324/755	479
	14	324/765	1552
	25	324/158.1	1119
	32	324/754	1675
	40	324/758	419
324/750.2	1	324/754	1675
	1	324/757	142
	1	324/760	449
	2	324/762	181
	2	324/763	517
	3	324/758	419
	5	324/761	338
	6	324/755	479
	7	324/158.1	1119
	7	324/765	1552
	11	324/754	1675
324/750.21	1	324/158.1	1119
	1	324/158.1	1119
	1	324/758	419
324/750.22	1	324/753	72
	1	324/757	142
	1	324/760	449
	1	324/765	1552
	1	324/766	95
	2	324/158.1	1119
	2	324/755	479
	2	324/758	419
	2	324/759	15
	3	324/770	234
	4	324/751	215
	4	324/752	156
	4	324/754	1675
	4	324/762	181

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New Classification	Number of ORs	Source Classification	Number of ORs
	6	324/765	1552
	7	324/761	338
	30	324/158.1	1119
	43	324/754	1675
	46	324/758	419
324/750.23	1	324/750	130
	1	324/751	215
	1	324/753	72
	1	324/756	53
	1	324/761	338
	1	324/762	181
	1	324/772	300
	2	324/158.1	1119
	2	324/750	130
	3	324/752	156
	3	324/758	419
	4	324/755	479
	5	324/158.1	1119
	9	324/765	1552
	14	324/754	1675
	23	324/758	419
324/750.24	1	324/754	1675
	1	324/761	338
	1	324/764	20
	1	324/770	234
	2	324/158.1	1119
	2	324/762	181
	3	324/755	479
	3	324/757	142
	3	324/761	338
	3	324/765	1552
	5	324/158.1	1119
	6	324/758	419
	10	324/758	419
	13	324/754	1675
324/750.25	1	324/751	215
	1	324/763	517
	1	324/771	90
	2	324/753	72
	2	324/754	1675
	2	324/758	419
	2	324/760	449
	2	324/772	300

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SOURCE CLASSIFICATION(S) OF PATENTS
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New Classification	Number of ORs	Source Classification	Number of ORs
	3	324/770	234
	4	324/756	53
	5	324/158.1	1119
	7	324/757	142
	9	324/762	181
	18	324/765	1552
	34	324/158.1	1119
	37	324/761	338
	60	324/755	479
	68	324/758	419
	93	324/754	1675
324/750.26	1	324/750	130
	1	324/751	215
	1	324/752	156
	2	324/757	142
	3	324/158.1	1119
	3	324/765	1552
	4	324/755	479
	4	324/761	338
	6	324/754	1675
	6	324/762	181
	14	324/754	1675
324/750.27	1	324/758	419
	1	324/763	517
	1	324/765	1552
	2	324/755	479
	2	324/762	181
	2	324/765	1552
	3	324/158.1	1119
	3	324/761	338
	13	324/158.1	1119
	21	324/754	1675
324/750.28	2	324/758	419
	2	324/760	449
324/750.29	1	324/755	479
	1	324/761	338
	1	324/765	1552
	4	324/754	1675
324/750.3	1	324/752	156
	1	324/753	72
	1	324/753	72
	1	324/758	419
	1	324/768	75

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New Classification	Number of ORs	Source Classification	Number of ORs
	1	324/769	169
	1	324/771	90
	1	324/772	300
	1	324/772	300
	2	324/751	215
	2	324/755	479
	2	324/755	479
	2	324/760	449
	2	324/766	95
	3	324/750	130
	3	324/758	419
	5	324/771	90
	7	324/767	184
	8	324/769	169
	14	324/754	1675
	14	324/770	234
	29	324/158.1	1119
	43	324/765	1552
	76	324/158.1	1119
	111	324/763	517
	145	324/765	1552
	217	324/763	517
324/754.01	1	324/158.1	1119
	2	324/758	419
	2	324/765	1552
	3	324/754	1675
324/754.02	1	324/158.1	1119
	1	324/753	72
	1	324/756	53
	1	324/764	20
	1	324/765	1552
	12	324/754	1675
324/754.03	1	324/750	130
	1	324/755	479
	1	324/756	53
	1	324/758	419
	1	324/768	75
	1	324/770	234
	2	324/753	72
	2	324/757	142
	2	324/761	338
	2	324/766	95
	2	324/769	169

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SOURCE CLASSIFICATION(S) OF PATENTS
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New Classification	Number of ORs	Source Classification	Number of ORs
	3	324/752	156
	3	324/759	15
	3	324/767	184
	4	324/158.1	1119
	4	324/750	130
	4	324/756	53
	4	324/765	1552
	7	324/758	419
	7	324/762	181
	7	324/770	234
	8	324/755	479
	9	324/757	142
	9	324/761	338
	12	324/763	517
	19	324/158.1	1119
	26	324/754	1675
	48	324/765	1552
	63	324/754	1675
324/754.04	1	324/754	1675
	1	324/756	53
	1	324/758	419
	1	324/758	419
	1	324/760	449
	1	324/762	181
	2	324/757	142
	3	324/765	1552
	8	324/754	1675
324/754.05	1	324/750	130
	1	324/752	156
	1	324/755	479
	1	324/761	338
	1	324/765	1552
	1	324/766	95
	1	324/769	169
	2	324/754	1675
	2	324/757	142
	6	324/765	1552
	7	324/755	479
	12	324/754	1675
324/754.06	1	324/750	130
	1	324/751	215
	1	324/761	338
	1	324/765	1552

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SOURCE CLASSIFICATION(S) OF PATENTS
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New Classification	Number of ORs	Source Classification	Number of ORs
	1	324/767	184
	2	324/158.1	1119
	2	324/752	156
	2	324/762	181
	4	324/753	72
	5	324/754	1675
324/754.07	1	324/158.1	1119
	1	324/752	156
	1	324/760	449
	1	324/761	338
	1	324/762	181
	1	324/763	517
	1	324/763	517
	1	324/766	95
	1	324/767	184
	2	324/770	234
	3	324/756	53
	3	324/758	419
	3	324/765	1552
	6	324/757	142
	6	324/758	419
	8	324/755	479
	13	324/761	338
	13	324/762	181
	17	324/158.1	1119
	35	324/765	1552
	36	324/754	1675
	143	324/754	1675
324/754.08	1	324/158.1	1119
	1	324/751	215
	1	324/754	1675
	1	324/756	53
	1	324/758	419
	1	324/762	181
	1	324/763	517
	1	324/765	1552
	3	324/757	142
	3	324/758	419
	6	324/158.1	1119
	6	324/755	479
	10	324/765	1552
	14	324/761	338
	23	324/754	1675

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New Classification	Number of ORs	Source Classification	Number of ORs
	23	324/755	479
324/754.09	1	324/751	215
	1	324/754	1675
	1	324/755	479
	1	324/755	479
	1	324/758	419
	1	324/761	338
	1	324/765	1552
	2	324/765	1552
	3	324/758	419
	4	324/158.1	1119
	6	324/754	1675
324/754.1	1	324/750	130
	1	324/754	1675
	1	324/755	479
	1	324/755	479
	1	324/758	419
	1	324/762	181
	1	324/763	517
	1	324/765	1552
	2	324/756	53
	2	324/757	142
	2	324/761	338
	3	324/158.1	1119
	5	324/756	53
	5	324/765	1552
	10	324/754	1675
324/754.11	1	324/755	479
	1	324/758	419
	1	324/763	517
	2	324/158.1	1119
	2	324/756	53
	5	324/762	181
	5	324/765	1552
	7	324/761	338
	9	324/757	142
	14	324/757	142
	25	324/754	1675
324/754.12	1	324/755	479
	1	324/758	419
	1	324/760	449
	1	324/761	338
	1	324/762	181

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SOURCE CLASSIFICATION(S) OF PATENTS
IN NEWLY ESTABLISHED SUBCLASSES REPORT

Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	2	324/754	1675
	2	324/765	1552
	5	324/754	1675
324/754.13	1	324/158.1	1119
	1	324/158.1	1119
	1	324/754	1675
	1	324/755	479
	1	324/758	419
	3	324/765	1552
	5	324/757	142
	9	324/761	338
	14	324/754	1675
324/754.14	1	324/756	53
	1	324/768	75
	1	324/772	300
	2	324/754	1675
	2	324/762	181
	3	324/757	142
	3	324/765	1552
	4	324/158.1	1119
	4	324/758	419
	8	324/755	479
	18	324/761	338
	31	324/754	1675
324/754.15	1	324/755	479
	1	324/757	142
	1	324/760	449
	2	324/158.1	1119
	2	324/762	181
	4	324/758	419
	4	324/761	338
	15	324/754	1675
324/754.16	1	324/755	479
	1	324/757	142
	2	324/758	419
	2	324/761	338
	2	324/765	1552
	3	324/158.1	1119
	8	324/754	1675
324/754.17	1	324/761	338
	2	324/754	1675
324/754.18	1	324/755	479
	1	324/756	53

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	1	324/757	142
	1	324/760	449
	1	324/764	20
	2	324/765	1552
	4	324/761	338
	5	324/755	479
	9	324/754	1675
	15	324/754	1675
324/754.19	1	324/763	517
	1	324/765	1552
	2	324/759	15
	2	324/765	1552
	3	324/158.1	1119
324/754.2	1	324/758	419
	1	324/762	181
	1	324/766	95
	2	324/755	479
	2	324/756	53
	5	324/761	338
	6	324/765	1552
	8	324/757	142
	17	324/754	1675
324/754.21	1	324/750	130
	1	324/752	156
	1	324/763	517
	1	324/769	169
	1	324/772	300
	2	324/753	72
	3	324/767	184
	3	324/770	234
	6	324/158.1	1119
	6	324/765	1552
	10	324/750	130
	19	324/751	215
324/754.22	1	324/158.1	1119
	1	324/750	130
	1	324/752	156
	1	324/766	95
	2	324/754	1675
	2	324/758	419
	3	324/767	184
	6	324/158.1	1119
	6	324/770	234

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	7	324/750	130
	7	324/752	156
	9	324/765	1552
	19	324/751	215
	127	324/751	215
324/754.23	1	324/158.1	1119
	1	324/751	215
	1	324/763	517
	1	324/763	517
	1	324/765	1552
	1	324/766	95
	1	324/772	300
	3	324/158.1	1119
	3	324/754	1675
	3	324/754	1675
	5	324/753	72
	5	324/766	95
	5	324/770	234
	7	324/751	215
	9	324/750	130
	14	324/767	184
	16	324/750	130
	16	324/752	156
	28	324/753	72
	37	324/765	1552
	68	324/752	156
324/754.24	1	324/750	130
	1	324/750	130
	1	324/752	156
	4	324/754	1675
324/754.25	1	324/158.1	1119
	4	324/765	1552
324/754.26	1	324/750	130
	1	324/758	419
	1	324/762	181
	1	324/767	184
	2	324/752	156
	2	324/765	1552
324/754.27	1	324/158.1	1119
	1	324/750	130
	1	324/752	156
	1	324/753	72
	1	324/769	169

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	2	324/766	95
	3	324/765	1552
	8	324/750	130
324/754.28	1	324/752	156
	1	324/766	95
	1	324/770	234
	2	324/754	1675
	2	324/761	338
	4	324/755	479
	10	324/765	1552
324/754.29	1	324/755	479
	1	324/763	517
	1	324/764	20
	2	324/754	1675
	3	324/750	130
	5	324/765	1552
	5	324/772	300
	6	324/750	130
324/754.31	1	324/750	130
	1	324/750	130
	1	324/762	181
	1	324/763	517
	1	324/765	1552
	1	324/767	184
	2	324/766	95
	5	324/765	1552
324/755.01	1	324/752	156
	1	324/753	72
	1	324/755	479
	1	324/756	53
	1	324/757	142
	1	324/760	449
	1	324/762	181
	1	324/765	1552
	1	324/770	234
	1	324/772	300
	2	324/761	338
	3	324/765	1552
	4	324/761	338
	5	324/758	419
	6	324/762	181
	13	324/754	1675
	55	324/754	1675

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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
324/755.02	1	324/755	479
	1	324/758	419
	1	324/761	338
	3	324/754	1675
	3	324/762	181
	4	324/158.1	1119
	6	324/761	338
	22	324/754	1675
324/755.03	1	324/158.1	1119
	1	324/763	517
	2	324/754	1675
	2	324/762	181
	3	324/754	1675
324/755.04	1	324/757	142
	1	324/761	338
	1	324/770	234
	3	324/754	1675
	8	324/754	1675
324/755.05	1	324/762	181
	1	324/764	20
	1	324/765	1552
	1	324/765	1552
	1	324/771	90
	2	324/158.1	1119
	2	324/756	53
	3	324/757	142
	4	324/762	181
	6	324/755	479
	6	324/758	419
	7	324/761	338
	10	324/754	1675
	46	324/754	1675
	52	324/761	338
324/755.06	1	324/756	53
	1	324/758	419
	1	324/760	449
	1	324/762	181
	3	324/762	181
	7	324/754	1675
	7	324/761	338
324/755.07	1	324/757	142
	1	324/761	338
	1	324/765	1552

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SOURCE CLASSIFICATION(S) OF PATENTS
IN NEWLY ESTABLISHED SUBCLASSES REPORT

Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	2	324/757	142
	3	324/758	419
	8	324/754	1675
	15	324/762	181
	19	324/754	1675
	24	324/762	181
324/755.08	1	324/757	142
	1	324/761	338
	1	324/761	338
	2	324/158.1	1119
	2	324/755	479
	7	324/754	1675
	8	324/754	1675
324/755.09	1	324/761	338
	1	324/762	181
	2	324/755	479
	2	324/758	419
	3	324/757	142
	3	324/765	1552
	7	324/754	1675
	23	324/754	1675
324/755.1	1	324/761	338
	1	324/763	517
	2	324/757	142
324/755.11	1	324/757	142
	1	324/758	419
	2	324/762	181
	4	324/761	338
	6	324/762	181
	10	324/761	338
	20	324/754	1675
	22	324/754	1675
324/756.01	1	324/750	130
	1	324/756	53
	1	324/761	338
	1	324/764	20
	1	324/765	1552
	1	324/767	184
	1	324/772	300
	2	324/755	479
	2	324/762	181
	2	324/763	517
	3	324/758	419

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	3	324/760	449
	4	324/758	419
	6	324/754	1675
	9	324/754	1675
	10	324/158.1	1119
	10	324/765	1552
	13	324/755	479
	20	324/158.1	1119
324/756.02	1	324/750	130
	1	324/758	419
	1	324/760	449
	1	324/760	449
	1	324/763	517
	1	324/766	95
	1	324/768	75
	1	324/771	90
	1	324/772	300
	2	324/767	184
	2	324/770	234
	3	324/762	181
	5	324/158.1	1119
	6	324/754	1675
	6	324/757	142
	6	324/763	517
	7	324/755	479
	7	324/765	1552
	8	324/758	419
	13	324/761	338
	41	324/754	1675
	43	324/158.1	1119
	45	324/765	1552
	120	324/755	479
324/756.03	1	324/755	479
	1	324/765	1552
	2	324/760	449
	3	324/756	53
	4	324/758	419
	5	324/158.1	1119
	5	324/158.1	1119
	5	324/757	142
	7	324/755	479
	8	324/765	1552
	10	324/758	419

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SOURCE CLASSIFICATION(S) OF PATENTS
IN NEWLY ESTABLISHED SUBCLASSES REPORT

Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	10	324/761	338
	22	324/762	181
	58	324/754	1675
	114	324/754	1675
324/756.04	1	324/755	479
	1	324/757	142
	1	324/765	1552
	1	324/768	75
	1	324/770	234
	3	324/758	419
	3	324/762	181
	3	324/765	1552
	4	324/755	479
	6	324/158.1	1119
	6	324/754	1675
	7	324/158.1	1119
	16	324/761	338
	24	324/754	1675
324/756.05	1	324/756	53
	1	324/767	184
	1	324/772	300
	2	324/770	234
	3	324/760	449
	4	324/158.1	1119
	4	324/757	142
	4	324/762	181
	5	324/763	517
	6	324/761	338
	11	324/758	419
	12	324/754	1675
	31	324/158.1	1119
	34	324/765	1552
	44	324/755	479
	49	324/754	1675
324/756.06	1	324/158.1	1119
	1	324/754	1675
	1	324/760	449
	1	324/769	169
	1	324/771	90
	2	324/754	1675
	2	324/768	75
	2	324/772	300
	3	324/158.1	1119

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SOURCE CLASSIFICATION(S) OF PATENTS
IN NEWLY ESTABLISHED SUBCLASSES REPORT

Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	6	324/765	1552
324/756.07	1	324/752	156
	1	324/758	419
	2	324/755	479
	2	324/757	142
	2	324/761	338
	2	324/770	234
	3	324/763	517
	7	324/755	479
	12	324/754	1675
	16	324/754	1675
	19	324/765	1552
	21	324/158.1	1119
	22	324/158.1	1119
324/757.01	1	324/755	479
	1	324/757	142
	1	324/758	419
	1	324/761	338
	1	324/763	517
	1	324/763	517
	1	324/765	1552
	3	324/754	1675
	4	324/158.1	1119
	4	324/765	1552
	19	324/158.1	1119
324/757.02	1	324/158.1	1119
	1	324/755	479
	1	324/761	338
	1	324/765	1552
	4	324/754	1675
	5	324/158.1	1119
324/757.03	1	324/158.1	1119
	1	324/755	479
	3	324/765	1552
	4	324/765	1552
	5	324/754	1675
	12	324/158.1	1119
324/757.04	1	324/754	1675
	1	324/755	479
	1	324/755	479
	1	324/758	419
	1	324/763	517
	1	324/765	1552

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	2	324/754	1675
	2	324/760	449
	3	324/158.1	1119
	4	324/765	1552
	18	324/158.1	1119
324/757.05	2	324/158.1	1119
	2	324/758	419
324/758.01	1	324/158.1	1119
	1	324/158.1	1119
	1	324/760	449
	2	324/757	142
	2	324/765	1552
324/758.02	1	324/770	234
324/758.03	1	324/158.1	1119
324/758.04	1	324/757	142
	2	324/158.1	1119
	2	324/754	1675
324/758.05	2	324/757	142
324/759.01	1	324/750	130
	1	324/759	15
	1	324/763	517
	1	324/769	169
	1	324/771	90
	1	324/772	300
	3	324/158.1	1119
	5	324/765	1552
324/759.02	1	324/764	20
	2	324/759	15
	3	324/158.1	1119
	6	324/765	1552
324/759.03	1	324/763	517
	1	324/765	1552
	1	324/767	184
	1	324/769	169
	2	324/158.1	1119
	3	324/770	234
	5	324/158.1	1119
	6	324/765	1552
324/76.11	1	324/768	75
	1	324/771	90
	1	324/772	300
	2	324/158.1	1119
	5	324/765	1552

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
324/76.19	1	324/750	130
324/760.01	1	324/158.1	1119
	1	324/752	156
	1	324/753	72
	1	324/765	1552
	1	324/767	184
	2	324/763	517
	39	324/770	234
	43	324/770	234
324/760.02	1	324/158.1	1119
	1	324/750	130
	1	324/754	1675
	1	324/764	20
	1	324/765	1552
	3	324/765	1552
	15	324/770	234
	53	324/770	234
324/761.01	1	324/752	156
	1	324/765	1552
	1	324/766	95
	1	324/771	90
	3	324/766	95
	8	324/767	184
324/762.01	1	324/750	130
	1	324/750	130
	1	324/751	215
	1	324/753	72
	1	324/754	1675
	1	324/755	479
	1	324/755	479
	1	324/758	419
	1	324/759	15
	1	324/761	338
	1	324/763	517
	1	324/767	184
	1	324/768	75
	1	324/769	169
	1	324/770	234
	2	324/752	156
	2	324/754	1675
	2	324/768	75
	2	324/772	300
	3	324/771	90

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	4	324/158.1	1119
	5	324/769	169
	12	324/763	517
	21	324/767	184
	22	324/766	95
	41	324/765	1552
	47	324/158.1	1119
	134	324/765	1552
324/762.02	1	324/756	53
	1	324/757	142
	1	324/760	449
	1	324/761	338
	1	324/763	517
	1	324/770	234
	2	324/753	72
	2	324/764	20
	2	324/766	95
	3	324/750	130
	3	324/752	156
	3	324/754	1675
	3	324/755	479
	3	324/771	90
	5	324/767	184
	6	324/754	1675
	9	324/769	169
	11	324/158.1	1119
	40	324/765	1552
	42	324/763	517
	63	324/158.1	1119
	156	324/765	1552
324/762.03	1	324/753	72
	1	324/754	1675
	1	324/755	479
	1	324/761	338
	1	324/768	75
	2	324/750	130
	2	324/766	95
	4	324/752	156
	5	324/765	1552
	5	324/769	169
	9	324/763	517
	11	324/158.1	1119
	37	324/765	1552

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SOURCE CLASSIFICATION(S) OF PATENTS
IN NEWLY ESTABLISHED SUBCLASSES REPORT

Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
324/762.04	1	324/755	479
	1	324/758	419
	1	324/763	517
	2	324/158.1	1119
	2	324/765	1552
	4	324/754	1675
324/762.05	1	324/754	1675
	1	324/760	449
	1	324/764	20
	1	324/766	95
	1	324/769	169
	1	324/770	234
	2	324/750	130
	2	324/752	156
	2	324/763	517
	2	324/769	169
	3	324/766	95
	4	324/158.1	1119
	4	324/158.1	1119
	5	324/758	419
	5	324/763	517
	5	324/767	184
	7	324/754	1675
	7	324/765	1552
	42	324/765	1552
324/762.06	1	324/158.1	1119
	1	324/754	1675
	1	324/757	142
	1	324/758	419
	1	324/760	449
	1	324/768	75
	2	324/158.1	1119
	5	324/765	1552
	7	324/765	1552
324/762.07	1	324/158.1	1119
	1	324/158.1	1119
	1	324/753	72
	1	324/765	1552
	1	324/765	1552
	1	324/770	234
	1	324/771	90
	2	324/769	169
	3	324/767	184

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	3	324/772	300
	6	324/766	95
	65	324/767	184
324/762.08	1	324/768	75
	1	324/771	90
	2	324/158.1	1119
	3	324/769	169
	6	324/766	95
	7	324/767	184
	9	324/769	169
	39	324/765	1552
	49	324/768	75
324/762.09	1	324/158.1	1119
	1	324/750	130
	1	324/756	53
	1	324/760	449
	1	324/768	75
	2	324/763	517
	3	324/765	1552
	4	324/768	75
	5	324/770	234
	6	324/766	95
	6	324/767	184
	7	324/158.1	1119
	15	324/769	169
	35	324/765	1552
	77	324/769	169
324/762.1	1	324/765	1552
	1	324/769	169
	1	324/769	169
	4	324/766	95
324/763.01	1	324/158.1	1119
	1	324/755	479
	1	324/756	53
	1	324/758	419
	1	324/758	419
	1	324/761	338
	1	324/766	95
	1	324/767	184
	2	324/755	479
	3	324/750	130
	3	324/765	1552
	5	324/763	517

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
	5	324/765	1552
	6	324/754	1675
	15	324/158.1	1119
324/763.02	1	324/158.1	1119
	1	324/764	20
	2	324/754	1675
324/764.01	1	324/763	517
	1	324/766	95
	1	324/766	95
	1	324/767	184
	1	324/769	169
	2	324/763	517
	3	324/765	1552
	5	324/772	300
	6	324/158.1	1119
	7	324/765	1552
	8	324/158.1	1119
	16	324/771	90
	38	324/771	90
324/765.01	1	324/158.1	1119
	4	324/158.1	1119
	19	324/772	300
	183	324/772	300
324/95	1	324/765	1552
	1	324/771	90
324/96	1	324/753	72
324/97	1	324/158.1	1119
	1	324/753	72
326/102	1	324/765	1552
326/33	1	324/765	1552
326/8	1	324/763	517
326/80	1	324/765	1552
327/116	1	324/753	72
327/172	1	324/772	300
327/543	1	324/765	1552
33/533	1	324/158.1	1119
33/534	1	324/772	300
333/26	1	324/754	1675
335/5	1	324/754	1675
340/584	1	324/755	479
340/645	1	324/767	184
340/815.87	1	324/770	234
340/870.02	1	324/158.1	1119

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SOURCE CLASSIFICATION(S) OF PATENTS
IN NEWLY ESTABLISHED SUBCLASSES REPORT

Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
345/179	1	324/754	1675
345/93	1	324/770	234
348/178	1	324/158.1	1119
353/99	1	324/158.1	1119
356/123	1	324/753	72
356/237.1	1	324/754	1675
356/237.5	1	324/750	130
	1	324/752	156
	1	324/754	1675
	1	324/765	1552
	1	324/770	234
	2	324/753	72
	3	324/158.1	1119
356/25	1	324/772	300
356/432	1	324/770	234
356/51	1	324/752	156
356/614	1	324/755	479
356/630	1	324/158.1	1119
359/368	1	324/752	156
361/100	1	324/158.1	1119
361/101	1	324/769	169
	2	324/765	1552
361/104	1	324/768	75
361/20	1	324/772	300
361/318	1	324/755	479
361/679.02	1	324/764	20
361/707	1	324/158.1	1119
361/728	1	324/763	517
361/737	1	324/765	1552
361/767	1	324/755	479
361/807	2	324/158.1	1119
361/809	1	324/158.1	1119
361/818	1	324/158.1	1119
361/823	1	324/158.1	1119
361/91.1	1	324/765	1552
361/93.9	1	324/767	184
365/185.18	1	324/158.1	1119
365/226	1	324/771	90
374/163	1	324/772	300
374/178	2	324/760	449
374/185	1	324/158.1	1119
	2	324/772	300
377/20	1	324/158.1	1119

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SOURCE CLASSIFICATION(S) OF PATENTS
IN NEWLY ESTABLISHED SUBCLASSES REPORT

Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
379/24	1	324/771	90
382/151	1	324/758	419
399/123	1	324/760	449
414/389	1	324/158.1	1119
438/110	2	324/763	517
438/14	1	324/766	95
438/15	1	324/158.1	1119
	1	324/765	1552
438/16	1	324/752	156
438/17	1	324/158.1	1119
	2	324/754	1675
	2	324/765	1552
438/18	1	324/763	517
	1	324/765	1552
438/5	1	324/158.1	1119
438/8	1	324/753	72
455/127.2	1	324/771	90
455/302	1	324/158.1	1119
607/28	1	324/158.1	1119
700/115	1	324/158.1	1119
700/297	1	324/760	449
702/104	1	324/158.1	1119
702/117	2	324/767	184
	3	324/765	1552
702/118	1	324/158.1	1119
	1	324/755	479
	1	324/765	1552
702/119	1	324/158.1	1119
702/180	1	324/158.1	1119
702/183	1	324/158.1	1119
702/58	1	324/765	1552
702/64	1	324/765	1552
702/81	1	324/765	1552
702/83	1	324/158.1	1119
703/14	1	324/760	449
	1	324/768	75
	1	324/769	169
705/11	1	324/158.1	1119
708/625	1	324/158.1	1119
716/126	1	324/158.1	1119
73/1.05	1	324/158.1	1119
73/1.08	1	324/158.1	1119
73/1.72	1	324/772	300

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SOURCE CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

New Classification	Number of ORs	Source Classification	Number of ORs
73/1.75	1	324/772	300
73/1.79	1	324/158.1	1119
73/114.59	1	324/772	300
73/121	1	324/772	300
73/25.01	1	324/750	130
73/29.01	1	324/763	517
73/504.12	1	324/158.1	1119
73/514.26	1	324/158.1	1119
73/514.39	1	324/772	300
73/627	1	324/765	1552
73/663	1	324/754	1675
73/862.193	1	324/772	300
73/862.31	1	324/772	300
73/865.9	1	324/772	300
850/1	1	324/754	1675
850/19	1	324/754	1675
	1	324/762	181
850/2	1	324/754	1675
850/27	1	324/158.1	1119
	1	324/750	130
850/29	1	324/754	1675
850/3	1	324/754	1675
850/56	1	324/751	215
850/8	1	324/754	1675
	2	324/751	215

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/750	130	324/750.01	1
324/158.1	1119	324/750.03	23
324/766	95	324/750.05	1
324/765	1552	324/750.16	11
324/751	215	324/750.26	1
324/750	130	324/750.26	1
324/769	169	324/754.27	1
324/772	300	324/754.29	5
324/757	142	324/755.09	3
324/758	419	324/755.09	2
324/754	1675	324/757.04	2
324/750	130	324/762.03	2
324/755	479	324/762.04	1
324/765	1552	324/763.01	3
324/754	1675	324/763.02	2
324/753	72	324/750.15	1
324/754	1675	324/750.3	14
324/158.1	1119	324/754.02	1
324/754	1675	324/754.05	12
324/158.1	1119	324/754.07	17
324/765	1552	324/754.25	4
324/762	181	324/754.26	1
324/761	338	324/756.02	13
324/760	449	324/756.05	3
324/758	419	324/756.07	1
324/757	142	324/758.04	1
324/763	517	324/762.01	12
324/760	449	324/750.03	79
324/768	75	324/750.03	1
324/765	1552	324/750.05	69
324/760	449	324/750.14	11
324/758	419	324/750.22	46
		324/750.24	10
		324/754.07	6
		324/754.08	3
324/754	1675	324/754.22	2
		324/755.02	22
324/762	181	324/755.06	1
324/763	517	324/756.02	6
324/761	338	324/756.03	10
324/750	130	324/759.01	1
324/772	300	324/759.01	1
324/158.1	1119	324/762.01	47

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
		324/765.01	4
324/754	1675	324/750.01	4
324/750	130	324/750.14	4
324/754	1675	324/750.2	11
324/158.1	1119	324/750.22	30
324/760	449	324/750.28	2
324/766	95	324/754.23	5
324/752	156	324/754.28	1
324/754	1675	324/755.01	55
324/758	419	324/755.07	3
324/769	169	324/756.06	1
324/754	1675	324/758.04	2
324/764	20	324/760.02	1
324/753	72	324/762.01	1
324/763	517	324/762.03	9
324/765	1552	324/762.04	2
324/767	184	324/762.07	65
324/755	479	324/750.05	27
324/750	130	324/750.11	1
324/762	181	324/750.16	4
324/753	72	324/750.23	1
324/158.1	1119	324/750.26	3
324/752	156	324/754.24	1
324/757	142	324/755.05	3
324/762	181	324/755.07	24
324/750	130	324/756.01	1
324/769	169	324/759.03	1
324/158.1	1119	324/760.01	1
324/765	1552	324/760.01	1
324/766	95	324/762.02	2
324/754	1675	324/750.03	25
324/753	72	324/750.11	1
324/765	1552	324/754.21	6
324/758	419	324/754.22	2
324/754	1675	324/755.08	8
324/758	419	324/757.04	1
		324/757.05	2
324/766	95	324/750.02	1
324/751	215	324/750.02	4
324/770	234	324/750.05	2
324/765	1552	324/750.23	9
		324/754.02	1
324/757	142	324/754.1	2

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/765	1552	324/754.18	2
324/750	130	324/754.22	7
324/754	1675	324/757.01	3
324/765	1552	324/759.02	6
324/761	338	324/762.03	1
324/158.1	1119	324/762.04	2
324/767	184	324/764.01	1
324/761	338	324/750.15	1
324/760	449	324/750.01	2
324/762	181	324/750.03	2
324/766	95	324/750.03	5
324/758	419	324/750.04	1
		324/750.07	2
324/753	72	324/750.16	2
324/772	300	324/750.16	1
324/755	479	324/750.22	2
324/764	20	324/750.24	1
324/762	181	324/754.03	7
324/763	517	324/754.1	1
324/756	53	324/754.11	2
324/763	517	324/754.23	1
324/756	53	324/755.05	2
324/769	169	324/762.1	1
324/758	419	324/763.01	1
324/766	95	324/763.01	1
324/772	300	324/764.01	5
324/765	1552	324/750.08	1
324/158.1	1119	324/756.04	7
		324/750.25	5
324/751	215	324/754.23	1
324/158.1	1119	324/756.06	1
324/758	419	324/762.01	1
324/760	449	324/750.04	1
324/758	419	324/750.24	6
324/750	130	324/754.29	3
324/761	338	324/755.09	1
324/755	479	324/756.01	2
324/754	1675	324/750.01	1
324/771	90	324/750.3	1
324/750	130	324/754.21	1
324/765	1552	324/762.03	5
324/760	449	324/762.06	1
324/767	184	324/762.07	3

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/158.1	1119	324/763.01	1
324/761	338	324/750.16	1
324/765	1552	324/757.02	1
		324/762.01	41
		324/754.08	1
324/766	95	324/761.01	1
324/754	1675	324/750.05	3
324/760	449	324/750.12	1
324/755	479	324/756.04	1
324/769	169	324/762.01	1
324/763	517	324/750.02	1
324/754	1675	324/750.02	1
		324/755.04	3
324/158.1	1119	324/762.09	1
324/772	300	73/121	1
324/750	130	850/27	1
324/772	300	324/244	1
324/770	234	356/432	1
324/767	184	324/537	1
324/158.1	1119	324/616	1
324/755	479	356/614	1
324/763	517	324/527	1
324/765	1552	324/699	1
324/772	300	324/113	1
324/158.1	1119	33/533	1
		324/244.1	1
324/765	1552	73/627	1
324/767	184	702/117	2
324/772	300	324/76.11	1
324/765	1552	438/15	1
324/770	234	345/93	1
324/754	1675	73/663	1
324/158.1	1119	850/27	1
		324/702	2
		361/100	1
324/763	517	324/537	1
324/765	1552	324/548	1
324/158.1	1119	324/527	1
324/772	300	310/419	1
		73/114.59	1
		374/163	1
324/158.1	1119	702/180	1
324/755	479	29/884	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/762	181	324/755.02	3
324/750	130	324/754.03	4
324/752	156	324/750.16	1
324/755	479	340/584	1
324/158.1	1119	356/237.5	3
		353/99	1
324/772	300	324/545	12
324/754	1675	324/699	1
324/158.1	1119	73/1.05	1
		324/600	1
324/753	72	324/750.07	1
324/767	184	324/750.08	1
324/765	1552	324/750.19	14
324/757	142	324/750.19	4
324/755	479	324/750.26	4
324/754	1675	324/750.27	21
324/762	181	324/754.06	2
324/756	53	324/754.07	3
324/761	338	324/754.11	7
		324/754.13	9
324/767	184	324/754.31	1
324/762	181	324/755.01	6
324/760	449	324/756.03	2
324/158.1	1119	324/756.07	21
324/770	234	324/762.01	1
324/769	169	324/762.05	1
324/766	95	324/750.15	1
324/758	419	324/750.02	9
324/762	181	324/750.02	1
324/761	338	324/750.08	1
324/754	1675	324/750.16	30
324/158.1	1119	324/750.24	5
324/757	142	324/754.03	9
324/751	215	324/754.23	7
324/770	234	324/755.04	1
324/768	75	324/756.04	1
324/765	1552	324/762.09	35
		324/750.02	21
324/755	479	324/750.02	5
324/754	1675	324/750.07	2
324/763	517	324/750.19	1
324/158.1	1119	324/750.21	1
324/763	517	324/750.3	217

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DISPOSITION CLASSIFICATION(S) OF PATENTS
FROM ABOLISHED SUBCLASSES REPORT

Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/769	169	324/754.03	2
324/754	1675	324/754.07	143
324/763	517	324/754.08	1
324/758	419	324/754.15	4
324/765	1552	324/754.22	9
324/772	300	324/754.23	1
324/765	1552	324/754.28	10
324/754	1675	324/755.06	7
324/757	142	324/755.08	1
		324/755.11	1
324/761	338	324/756.04	16
324/767	184	324/761.01	8
324/756	53	324/762.02	1
324/750	130	324/762.02	3
324/767	184	324/750.05	3
324/762	181	324/750.09	2
324/758	419	324/750.18	9
		324/750.2	3
324/755	479	324/750.25	60
324/756	53	324/754.02	1
324/770	234	324/754.03	7
324/754	1675	324/756.03	114
324/769	169	324/762.08	3
324/763	517	324/764.01	1
324/752	156	324/750.03	5
324/754	1675	324/750.13	3
324/750	130	324/750.23	2
324/765	1552	324/750.25	18
324/768	75	324/750.3	1
324/751	215	324/750.3	2
324/761	338	324/754.03	9
324/758	419	324/754.16	2
324/753	72	324/754.27	1
324/765	1552	324/761.01	1
324/755	479	324/762.02	3
324/761	338	324/750.05	5
324/754	1675	324/754.03	63
324/765	1552	324/754.04	3
		324/754.08	10
324/757	142	324/754.08	3
324/754	1675	324/754.15	15
324/762	181	324/754.15	2
324/757	142	324/754.2	8

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DISPOSITION CLASSIFICATION(S) OF PATENTS
FROM ABOLISHED SUBCLASSES REPORT

Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/770	234	324/754.21	3
		324/754.23	5
324/764	20	324/754.29	1
324/765	1552	324/755.01	3
		324/756.06	6
324/755	479	324/756.07	7
324/761	338	324/757.01	1
324/763	517	324/762.04	1
324/750	130	324/750.05	2
324/765	1552	324/750.18	3
324/757	142	324/750.24	3
324/761	338	324/754.05	1
324/765	1552	324/754.09	2
324/754	1675	324/754.14	31
324/755	479	324/754.29	1
324/760	449	324/756.02	1
324/754	1675	324/756.06	2
324/768	75	324/762.06	1
324/756	53	324/763.01	1
324/755	479	324/763.01	2
324/769	169	324/750.06	1
324/761	338	324/750.29	1
324/770	234	324/754.07	2
324/752	156	324/754.07	1
324/754	1675	324/754.13	14
324/760	449	324/754.15	1
324/765	1552	324/754.23	37
		324/756.01	10
324/771	90	324/756.06	1
324/757	142	324/758.05	2
324/770	234	324/762.07	1
324/158.1	1119	324/750.03	4
324/763	517	324/750.11	1
324/765	1552	324/760.02	1
324/754	1675	324/762.02	3
324/763	517	324/750.01	1
324/758	419	324/750.19	6
324/765	1552	324/757.01	1
324/760	449	324/750.05	14
324/758	419	324/754.09	1
324/754	1675	324/755.09	7
		324/756.05	12
324/769	169	324/762.07	2

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/770	234	324/750.01	1
324/765	1552	324/750.22	1
324/757	142	324/755.01	1
324/758	419	324/754.03	1
324/754	1675	324/754.03	26
324/750	130	324/754.03	1
324/158.1	1119	324/762.06	1
		324/750.05	6
324/765	1552	324/754.09	1
324/768	75	324/762.09	1
324/754	1675	324/750.26	6
324/765	1552	324/754.1	1
324/767	184	324/762.01	1
324/772	300	374/185	2
324/754	1675	438/17	2
324/158.1	1119	257/682	1
		204/228.7	1
		324/550	1
324/754	1675	333/26	1
324/750	130	324/719	1
324/771	90	307/64	1
324/158.1	1119	438/5	1
324/765	1552	702/118	1
324/763	517	326/8	1
324/771	90	324/537	1
324/768	75	324/66	1
324/765	1552	324/693	1
		323/282	1
324/753	72	324/97	1
324/763	517	73/29.01	1
324/772	300	324/388	1
324/760	449	374/178	2
324/753	72	327/116	1
324/754	1675	324/117 R	1
324/757	142	257/48	1
324/755	479	361/767	1
324/769	169	361/101	1
324/754	1675	29/755	1
324/158.1	1119	324/142	2
324/754	1675	850/3	1
324/158.1	1119	324/130	1
		324/97	1
		73/504.12	1

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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/771	90	365/226	1
324/158.1	1119	324/76.11	2
		702/183	1
324/765	1552	326/33	1
324/753	72	356/123	1
324/158.1	1119	324/71.1	1
324/754	1675	324/754.2	17
324/158.1	1119	324/750.19	25
324/751	215	324/754.06	1
324/766	95	324/537	3
324/771	90	324/431	1
324/765	1552	361/91.1	1
324/754	1675	850/8	1
324/158.1	1119	324/248	1
324/765	1552	324/650	1
324/158.1	1119	702/119	1
324/772	300	242/357	1
324/754	1675	850/29	1
324/765	1552	702/117	3
324/760	449	324/750.02	1
324/158.1	1119	324/750.13	5
324/762	181	324/750.23	1
324/761	338	324/750.23	1
324/771	90	324/750.25	1
324/761	338	324/750.27	3
324/758	419	324/750.3	3
324/761	338	324/754.14	18
324/760	449	324/754.18	1
324/752	156	324/754.21	1
324/763	517	324/755.1	1
324/758	419	324/756.01	3
324/754	1675	324/756.02	41
324/750	130	324/756.02	1
324/754	1675	324/762.02	6
324/771	90	324/762.08	1
324/758	419	324/750.19	40
324/766	95	324/750.22	1
324/158.1	1119	324/750.25	34
324/770	234	324/750.25	3
324/755	479	324/750.29	1
324/754	1675	324/754.06	5
324/158.1	1119	324/754.11	2
324/761	338	324/754.12	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/759	15	324/754.19	2
324/765	1552	324/756.07	19
324/764	20	324/759.02	1
324/769	169	324/764.01	1
324/772	300	324/750.01	3
324/760	449	324/750.04	3
324/755	479	324/750.09	2
324/758	419	324/750.23	23
		324/754.09	3
324/754	1675	324/754.11	25
324/755	479	324/754.14	8
324/772	300	324/754.14	1
324/767	184	324/754.23	14
324/757	142	324/755.07	2
324/755	479	324/756.01	13
324/756	53	324/756.03	3
324/760	449	324/757.04	2
324/753	72	324/760.01	1
324/757	142	324/762.02	1
324/769	169	324/762.03	5
324/767	184	324/762.05	5
324/766	95	324/762.07	6
324/756	53	324/750.02	1
324/758	419	324/750.05	8
324/750	130	324/750.16	3
324/752	156	324/750.19	2
324/765	1552	324/750.24	3
324/762	181	324/750.26	6
		324/754.2	1
324/760	449	324/762.02	1
		324/762.09	1
324/754	1675	324/763.01	6
324/756	53	324/750.01	2
324/760	449	324/750.07	29
324/758	419	324/750.13	1
324/754	1675	324/750.14	19
324/770	234	324/750.19	1
324/761	338	324/750.22	7
324/756	53	324/750.25	4
324/158.1	1119	324/754.03	19
324/765	1552	324/754.06	1
324/762	181	324/754.14	2
324/758	419	324/757.01	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/755	479	324/762.03	1
324/769	169	324/750.01	2
324/158.1	1119	324/750.07	6
324/765	1552	324/750.12	1
324/755	479	324/750.16	7
324/765	1552	324/750.2	7
324/755	479	324/750.2	6
324/754	1675	324/750.29	4
324/760	449	324/754.04	1
324/767	184	324/754.06	1
324/754	1675	324/754.16	8
324/751	215	324/754.22	127
324/765	1552	324/754.27	3
324/772	300	324/765.01	183
324/755	479	324/750.03	8
324/158.1	1119	324/750.05	24
324/755	479	324/750.06	1
324/158.1	1119	324/750.09	2
324/755	479	324/750.1	2
324/766	95	324/754.07	1
324/761	338	324/754.18	4
324/750	130	324/760.02	1
324/765	1552	324/762.08	39
324/761	338	324/763.01	1
324/760	449	324/750.1	3
324/761	338	324/750.2	5
324/765	1552	324/750.29	1
		324/754.05	6
		324/754.1	5
324/763	517	324/756.01	2
324/770	234	324/756.05	2
324/158.1	1119	324/758.03	1
324/768	75	324/762.01	2
324/755	479	324/762.01	1
324/765	1552	324/750.16	1
324/761	338	324/755.02	1
		324/755.11	4
324/755	479	324/756.02	7
324/158.1	1119	324/756.07	22
324/754	1675	324/757.04	1
324/765	1552	324/750.14	2
324/754	1675	324/750.16	7
324/158.1	1119	324/754.07	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/758	419	324/756.03	4
324/765	1552	324/759.03	1
		324/762.09	3
324/760	449	324/750.13	4
324/158.1	1119	324/757.01	4
		324/762.01	4
324/758	419	324/754.01	2
324/754	1675	324/754.08	1
		324/762.05	7
		324/750.03	5
		324/754.12	2
324/751	215	324/754.22	19
324/754	1675	324/755.08	7
324/767	184	324/756.01	1
324/754	1675	324/750.25	2
324/755	479	324/754.08	6
		324/763.01	1
324/760	449	324/750.01	3
324/158.1	1119	324/754.08	1
324/754	1675	324/754.13	1
324/765	1552	324/756.02	7
324/754	1675	324/756.07	12
324/764	20	324/763.02	1
324/769	169	324/120	1
324/768	75	324/76.11	1
324/761	338	324/71.1	1
324/765	1552	257/48	1
324/755	479	702/118	1
324/766	95	324/693	1
324/765	1552	324/658	2
324/158.1	1119	205/791	1
324/760	449	399/123	1
324/758	419	324/686	1
324/752	156	250/370.11	1
324/765	1552	361/737	1
324/770	234	324/537	1
324/754	1675	356/237.1	1
324/752	156	438/16	1
324/772	300	324/217	1
		324/207.25	1
324/765	1552	702/64	1
324/158.1	1119	324/698	1
		361/809	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/769	169	324/750.3	8
324/752	156	324/750.22	4
324/755	479	324/538	1
324/772	300	324/750.03	1
324/765	1552	324/750.08	7
324/754	1675	324/750.1	2
324/767	184	324/750.19	1
324/758	419	324/750.21	1
324/765	1552	324/750.26	3
324/158.1	1119	324/754.25	1
324/758	419	324/756.02	8
324/762	181	324/756.04	3
324/763	517	324/756.05	5
324/750	130	324/762.01	1
		324/763.01	3
324/770	234	324/750.16	2
324/158.1	1119	324/750.2	7
324/759	15	324/754.03	3
324/762	181	324/754.04	1
324/761	338	324/754.06	1
324/762	181	324/754.11	5
324/755	479	324/754.13	1
324/754	1675	324/754.18	15
324/756	53	324/754.18	1
324/758	419	324/754.2	1
324/752	156	324/756.07	1
324/158.1	1119	324/757.04	18
324/752	156	324/761.01	1
324/770	234	324/762.05	1
324/763	517	324/750.15	4
324/752	156	324/750.05	1
324/767	184	324/750.09	2
324/761	338	324/750.24	3
324/760	449	324/754.07	1
324/770	234	324/760.01	43
324/769	169	324/762.09	77
324/771	90	324/764.01	38
324/765	1552	324/750.09	6
324/760	449	324/750.11	6
324/158.1	1119	324/750.14	10
324/758	419	324/750.27	1
324/761	338	324/754.17	1
324/755	479	324/755.05	6

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Source Classification	Number of ORs	New Classification	Number of ORs
324/759	15	324/762.01	1
324/765	1552	324/762.03	37
324/766	95	324/762.08	6
324/158.1	1119	324/750.01	34
324/763	517	324/750.05	15
324/754	1675	324/750.09	5
324/763	517	324/750.14	1
324/757	142	324/750.16	2
324/751	215	324/750.18	1
324/765	1552	324/754.03	48
324/753	72	324/754.06	4
324/754	1675	324/754.1	10
324/758	419	324/754.14	4
324/765	1552	324/754.26	2
324/755	479	324/755.02	1
324/757	142	324/755.04	1
324/758	419	324/756.05	11
324/770	234	324/760.02	53
324/763	517	324/762.02	42
324/758	419	324/750.01	4
324/762	181	324/750.2	2
324/751	215	324/750.22	4
324/763	517	324/750.27	1
324/757	142	324/754.05	2
		324/754.18	1
324/767	184	324/756.02	2
324/771	90	324/759.01	1
		324/761.01	1
324/755	479	324/750.24	3
324/770	234	324/750.24	1
324/758	419	324/750.25	68
324/761	338	324/750.26	4
324/158.1	1119	324/754.06	2
		324/754.09	4
324/750	130	324/754.1	1
324/758	419	324/755.01	5
324/158.1	1119	324/755.05	2
324/762	181	324/756.02	3
324/755	479	324/756.04	4
324/761	338	324/756.07	2
324/763	517	324/756.07	3
324/765	1552	324/759.01	5
		324/764.01	3

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Source Classification	Number of ORs	New Classification	Number of ORs
324/763	517	324/750.02	7
324/756	53	324/750.18	1
324/753	72	324/750.22	1
324/750	130	324/754.06	1
324/755	479	324/754.07	8
324/158.1	1119	324/754.08	6
324/758	419	324/754.11	1
		324/754.26	1
324/761	338	324/755.01	4
324/758	419	324/755.02	1
		324/755.06	1
324/761	338	324/755.08	1
324/754	1675	324/756.04	24
324/158.1	1119	324/756.05	31
324/767	184	324/762.01	21
		324/762.02	5
324/158.1	1119	324/762.05	4
324/765	1552	324/762.06	7
324/158.1	1119	324/750.02	5
324/758	419	324/750.3	1
324/755	479	324/754.05	1
324/754	1675	324/754.09	1
324/762	181	324/755.03	2
324/761	338	324/755.05	7
324/754	1675	324/756.02	6
324/763	517	324/762.05	2
324/764	20	324/756.01	1
324/763	517	324/762.01	1
324/755	479	324/754.03	1
324/754	1675	324/754.04	1
324/758	419	324/754.07	3
324/752	156	324/754.23	16
324/753	72	324/754.23	5
324/762	181	324/755.11	6
324/763	517	324/756.02	1
324/765	1552	324/750.09	1
324/760	449	324/750.11	2
324/754	1675	324/755.01	13
324/761	338	324/755.07	1
324/754	1675	324/756.01	6
324/158.1	1119	324/754.03	4
324/762	181	324/755.07	15
324/763	517	324/762.02	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/758	419	324/762.05	5
324/760	449	324/750.2	1
324/158.1	1119	324/757.02	1
324/763	517	324/760.01	2
324/757	142	324/762.06	1
324/758	419	324/750.16	7
324/754	1675	324/754.14	2
324/758	419	324/762.06	1
324/760	449	324/750.08	6
		324/750.1	1
324/765	1552	324/754.05	1
		324/754.23	1
		324/756.01	1
324/767	184	361/93.9	1
324/158.1	1119	438/15	1
		29/874	1
324/765	1552	324/719	3
324/753	72	324/96	1
324/158.1	1119	324/525	1
		250/338.4	1
324/772	300	324/134	1
324/771	90	324/76.11	1
324/765	1552	361/101	2
324/158.1	1119	361/707	1
324/765	1552	326/80	1
324/158.1	1119	348/178	1
324/754	1675	850/1	1
324/767	184	324/549	1
324/158.1	1119	361/807	2
		324/538	3
324/765	1552	324/663	1
		356/237.5	1
324/752	156	359/368	1
324/772	300	324/107	1
324/158.1	1119	324/548	1
324/772	300	324/126	1
324/760	449	700/297	1
324/771	90	324/550	2
324/158.1	1119	705/11	1
324/770	234	340/815.87	1
324/750	130	324/724	1
324/770	234	324/750.03	2
324/758	419	29/874	2

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/158.1	1119	307/31	1
		438/17	1
324/772	300	324/115	1
324/754	1675	324/724	1
324/158.1	1119	365/185.18	1
324/765	1552	438/17	2
324/158.1	1119	73/514.26	1
324/765	1552	324/690	1
324/757	142	324/750.01	1
324/765	1552	324/750.06	3
324/754	1675	324/750.19	32
		324/750.23	14
324/760	449	324/750.25	2
324/758	419	324/754.12	1
324/756	53	324/754.14	1
324/755	479	324/754.16	1
324/761	338	324/754.2	5
		324/755.02	6
		324/756.01	1
324/769	169	324/759.01	1
324/765	1552	324/760.02	3
		324/762.02	156
324/752	156	324/762.02	3
324/767	184	324/762.09	6
324/769	169	324/750.03	7
324/751	215	324/750.03	2
324/759	15	324/750.16	1
324/757	142	324/750.26	2
324/158.1	1119	324/750.3	76
324/752	156	324/750.3	1
324/767	184	324/754.03	3
324/755	479	324/754.1	1
324/762	181	324/754.1	1
		324/755.05	4
324/158.1	1119	324/756.06	3
324/765	1552	324/757.01	4
		324/759.03	6
324/771	90	324/762.01	3
324/766	95	324/762.09	6
324/760	449	324/750.06	8
324/158.1	1119	324/750.11	1
324/757	142	324/750.22	1
324/750	130	324/750.3	3

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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/754	1675	324/754.02	12
324/756	53	324/754.04	1
324/766	95	324/754.05	1
324/755	479	324/754.18	5
		324/754.28	4
324/762	181	324/755.11	2
324/158.1	1119	324/756.01	20
324/765	1552	324/756.05	34
324/762	181	324/756.05	4
324/158.1	1119	324/760.02	1
324/766	95	324/762.01	22
324/158.1	1119	324/762.02	63
324/766	95	324/764.01	1
324/753	72	324/754.02	1
324/765	1552	324/754.12	2
		324/754.19	2
		324/754.31	5
324/755	479	324/755.08	2
324/765	1552	324/757.03	4
324/158.1	1119	324/763.01	15
324/770	234	324/750.11	1
324/753	72	324/750.19	1
324/761	338	324/750.25	37
324/772	300	324/754.21	1
324/766	95	324/754.22	1
324/754	1675	324/754.24	4
324/750	130	324/754.24	1
324/765	1552	324/754.29	5
324/752	156	324/762.03	4
324/754	1675	324/762.05	1
324/772	300	324/750.02	2
324/758	419	324/754.03	7
324/769	169	324/754.05	1
324/756	53	324/755.01	1
324/755	479	324/755.09	2
324/158.1	1119	324/757.02	5
		324/757.05	2
324/766	95	324/761.01	3
324/758	419	324/762.04	1
324/767	184	324/763.01	1
324/761	338	324/750.14	1
		324/750.19	4
		324/754.08	14

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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/757	142	324/754.13	5
324/771	90	324/755.05	1
324/756	53	324/755.06	1
324/768	75	324/756.02	1
324/757	142	324/756.04	1
324/755	479	324/757.01	1
		324/757.02	1
324/765	1552	324/757.04	4
324/763	517	324/762.09	2
324/768	75	324/762.09	4
324/766	95	324/762.1	4
324/751	215	324/750.12	1
324/763	517	324/754.31	1
324/754	1675	324/755.04	8
324/755	479	324/756.05	44
324/754	1675	324/757.02	4
324/753	72	324/762.03	1
324/758	419	324/756.01	4
324/754	1675	324/757.03	5
324/765	1552	324/762.02	40
324/760	449	324/750.18	1
324/158.1	1119	324/750.24	2
		324/750.27	3
324/757	142	324/754.03	2
324/754	1675	324/754.18	9
324/765	1552	324/750.01	3
		324/750.02	2
		324/750.05	7
324/760	449	324/750.06	12
324/765	1552	324/750.3	43
324/754	1675	324/754.07	36
324/757	142	324/754.11	9
		324/755.07	1
324/754	1675	324/762.06	1
324/158.1	1119	324/762.08	2
324/771	90	324/764.01	16
324/750	130	324/754.27	1
324/754	1675	324/762.01	1
324/765	1552	324/754.03	4
324/752	156	324/754.05	1
324/754	1675	324/754.1	1
		324/755.05	10
324/770	234	324/760.02	15

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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/754	1675	324/760.02	1
324/758	419	324/750.01	1
324/769	169	324/750.01	1
324/754	1675	324/750.22	4
324/765	1552	324/750.27	2
324/755	479	324/756.07	2
324/758	419	324/750.25	2
324/750	130	324/754.23	9
324/754	1675	324/756.06	1
324/750	130	324/750.02	1
324/761	338	324/754.07	1
324/754	1675	324/756.04	6
324/755	479	324/757.03	1
324/772	300	356/25	1
324/158.1	1119	702/118	1
324/764	20	361/679.02	1
324/763	517	324/613	1
324/770	234	356/237.5	1
324/772	300	318/490	1
324/763	517	257/686	1
324/753	72	324/244.1	1
324/158.1	1119	374/185	1
		361/823	1
324/754	1675	324/391	1
324/751	215	324/411	1
324/158.1	1119	324/415	1
324/754	1675	29/874	2
324/765	1552	324/126	3
324/752	156	356/51	1
324/754	1675	356/237.5	1
324/765	1552	323/268	1
324/772	300	318/146	1
324/754	1675	29/828	1
324/771	90	323/265	1
324/765	1552	324/105	1
		324/230	1
324/158.1	1119	324/133	1
324/772	300	324/551	1
324/766	95	438/14	1
324/751	215	850/8	2
324/765	1552	324/117 H	1
324/158.1	1119	73/1.08	1
324/765	1552	702/58	1

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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
		324/537	4
324/158.1	1119	702/83	1
		324/117 H	2
		324/66	1
324/759	15	324/750.22	2
324/760	449	324/750.08	58
324/158.1	1119	324/762.02	11
324/763	517	438/18	1
324/765	1552	324/240	1
324/750	130	324/207.13	1
324/765	1552	310/361	1
324/772	300	327/172	1
		73/862.31	1
324/754	1675	29/884	2
324/158.1	1119	361/818	1
324/772	300	318/798	1
324/753	72	356/237.5	2
324/764	20	324/750.15	7
324/758	419	324/750.03	6
324/158.1	1119	324/750.08	9
324/770	234	324/750.12	1
324/754	1675	324/750.18	7
324/770	234	324/750.22	3
324/767	184	324/750.3	7
324/756	53	324/754.08	1
324/757	142	324/754.15	1
324/755	479	324/754.15	1
324/763	517	324/754.19	1
324/761	338	324/755.05	52
		324/755.11	10
324/755	479	324/756.02	120
324/158.1	1119	324/757.03	1
324/770	234	324/759.03	3
324/772	300	324/762.01	2
324/750	130	324/762.05	2
324/753	72	324/762.07	1
324/754	1675	324/750.04	1
324/752	156	324/750.08	1
324/765	1552	324/750.14	7
324/755	479	324/750.18	1
324/757	142	324/750.25	7
324/766	95	324/750.3	2
324/158.1	1119	324/754.01	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/752	156	324/754.03	3
324/763	517	324/757.01	1
324/767	184	324/759.03	1
324/761	338	324/762.01	1
324/760	449	324/750.05	112
324/763	517	324/750.16	2
324/769	169	324/750.16	1
324/752	156	324/750.23	3
324/765	1552	324/750.3	145
324/756	53	324/754.2	2
324/750	130	324/754.29	6
324/754	1675	324/755.07	19
		324/755.09	23
324/768	75	324/756.06	2
		324/750.02	2
324/765	1552	324/750.07	2
324/769	169	324/750.07	1
324/754	1675	324/750.11	1
324/158.1	1119	324/750.18	5
324/762	181	324/750.19	1
		324/750.22	4
324/760	449	324/754.12	1
324/750	130	324/754.21	10
324/767	184	324/754.22	3
324/754	1675	324/754.28	2
		324/756.01	9
324/765	1552	324/756.03	8
324/754	1675	324/756.05	49
324/767	184	324/756.05	1
324/757	142	324/757.01	1
324/754	1675	324/762.01	2
324/766	95	324/762.05	3
324/767	184	324/750.02	2
324/763	517	324/750.08	1
324/765	1552	324/750.17	2
324/757	142	324/750.2	1
324/753	72	324/750.25	2
324/756	53	324/754.03	4
324/758	419	324/754.04	1
324/764	20	324/754.18	1
324/761	338	324/754.28	2
324/750	130	324/754.31	1
324/766	95	324/754.31	2

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DISPOSITION CLASSIFICATION(S) OF PATENTS
FROM ABOLISHED SUBCLASSES REPORT

Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/770	234	324/755.01	1
324/755	479	324/756.03	7
324/756	53	324/756.05	1
324/766	95	324/762.03	2
324/765	1552	324/762.05	42
324/755	479	324/750.14	2
324/765	1552	324/750.27	1
324/750	130	324/754.05	1
324/757	142	324/754.07	6
		324/754.16	1
324/158.1	1119	324/754.23	1
324/761	338	324/755.06	7
324/764	20	324/762.02	2
324/772	300	324/762.07	3
324/770	234	324/762.09	5
324/158.1	1119	324/750.15	6
324/754	1675	324/750.05	24
324/750	130	324/750.07	1
324/758	419	324/750.16	19
324/754	1675	324/750.17	2
		324/750.25	93
324/763	517	324/750.25	1
324/752	156	324/750.26	1
324/755	479	324/754.08	23
324/765	1552	324/754.13	3
324/757	142	324/754.14	3
324/158.1	1119	324/754.16	3
324/754	1675	324/754.17	2
324/751	215	324/754.21	19
324/763	517	324/754.21	1
324/750	130	324/754.23	16
324/766	95	324/754.27	2
324/752	156	324/755.01	1
324/760	449	324/756.01	3
324/756	53	324/756.01	1
324/772	300	324/756.06	2
324/757	142	324/756.07	2
324/755	479	324/757.04	1
324/763	517	324/759.01	1
324/771	90	324/762.07	1
324/765	1552	324/762.07	1
		324/750.15	7
324/754	1675	324/750.02	13

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/756	53	324/750.05	1
324/760	449	324/750.09	31
324/765	1552	324/750.11	5
324/751	215	324/750.19	6
324/754	1675	324/750.26	14
324/763	517	324/754.03	12
324/752	156	324/754.26	2
324/158.1	1119	324/756.03	5
324/770	234	324/756.04	1
324/757	142	324/758.01	2
324/752	156	324/760.01	1
		324/762.01	2
324/754	1675	324/750.19	2
324/765	1552	324/763.01	5
324/158.1	1119	324/750.3	29
		324/757.04	3
324/760	449	324/750.03	5
324/761	338	324/750.13	1
324/758	419	324/750.22	2
324/763	517	324/750.3	111
324/158.1	1119	324/756.02	5
		324/765.01	1
324/754	1675	324/750.2	1
324/158.1	1119	324/750.22	2
324/766	95	324/762.05	1
324/768	75	324/762.08	1
324/158.1	1119	324/750.01	5
324/752	156	324/750.03	1
324/763	517	324/750.05	2
324/756	53	324/754.03	1
324/752	156	324/754.22	1
324/754	1675	324/754.29	2
324/765	1552	324/757.04	1
324/158.1	1119	324/759.03	2
324/760	449	324/750.09	12
324/758	419	324/750.28	2
324/764	20	324/755.05	1
324/762	181	324/755.09	1
324/765	1552	324/123 R	1
		324/301	1
324/752	156	324/238	1
324/754	1675	345/179	1
324/158.1	1119	702/104	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
FROM ABOLISHED SUBCLASSES REPORT

Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/754	1675	29/593	1
324/757	142	324/457	1
324/754	1675	850/2	1
324/772	300	324/139	1
324/756	53	324/551	1
324/772	300	73/1.75	1
324/768	75	703/14	1
324/766	95	324/642	1
324/754	1675	29/846	2
324/158.1	1119	414/389	1
324/772	300	324/380	2
324/158.1	1119	324/658	1
324/752	156	324/71.5	1
324/754	1675	850/19	1
324/771	90	324/95	1
324/158.1	1119	324/126	2
324/771	90	200/1 V	1
324/772	300	324/426	1
		324/402	1
		318/433	1
324/158.1	1119	324/656	1
		324/693	1
324/765	1552	702/81	1
324/158.1	1119	324/713	1
324/762	181	850/19	1
324/772	300	33/534	1
		73/865.9	1
324/755	479	361/318	1
324/750	130	324/468	1
324/762	181	324/755.06	3
324/768	75	324/762.01	1
324/752	156	356/237.5	1
324/753	72	438/8	1
324/765	1552	324/95	1
324/771	90	324/127	1
324/158.1	1119	29/759	1
		607/28	1
		324/750.02	43
324/767	184	324/750.03	4
324/772	300	324/750.23	1
324/762	181	324/750.25	9
324/755	479	324/754.05	7
324/772	300	324/755.01	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/766	95	324/756.02	1
324/770	234	324/762.02	1
324/769	169	324/762.02	9
324/765	1552	324/762.1	1
324/763	517	324/763.01	5
324/750	130	324/750.15	1
324/763	517	324/750.01	4
324/765	1552	324/750.03	51
324/762	181	324/750.24	2
324/158.1	1119	324/750.27	13
324/756	53	324/754.1	5
324/158.1	1119	324/754.14	4
324/761	338	324/754.16	2
324/755	479	324/755.01	1
324/765	1552	324/755.05	1
324/759	15	324/759.02	2
324/764	20	324/762.05	1
324/765	1552	324/750.01	25
324/769	169	324/750.02	2
324/757	142	324/750.05	7
		324/750.11	1
324/760	449	324/750.13	2
324/755	479	324/750.19	7
		324/754.03	8
324/765	1552	324/754.07	35
324/755	479	324/754.09	1
324/757	142	324/754.11	14
324/769	169	324/754.21	1
324/752	156	324/754.23	68
324/761	338	324/755.04	1
324/158.1	1119	324/756.02	43
324/761	338	324/756.05	6
324/158.1	1119	324/762.03	11
324/756	53	324/762.09	1
324/770	234	324/750.02	1
324/765	1552	324/750.1	2
324/751	215	324/750.14	6
324/755	479	324/750.3	2
324/753	72	324/754.03	2
324/751	215	324/754.08	1
324/760	449	324/755.01	1
324/762	181	324/756.01	2
324/751	215	324/750.01	2

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DISPOSITION CLASSIFICATION(S) OF PATENTS
FROM ABOLISHED SUBCLASSES REPORT

Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/761	338	324/750.16	4
324/757	142	324/754.04	2
324/754	1675	324/754.08	23
324/752	156	324/754.22	7
324/772	300	324/756.05	1
324/765	1552	324/762.01	134
324/753	72	324/762.02	2
324/158.1	1119	324/764.01	6
324/763	517	324/750.03	2
324/158.1	1119	324/750.04	1
324/758	419	324/750.17	2
324/759	15	324/750.19	3
324/750	130	324/750.19	2
324/763	517	324/750.2	2
324/754	1675	324/750.22	43
324/763	517	324/754.07	1
324/750	130	324/754.26	1
324/770	234	324/754.28	1
324/762	181	324/754.31	1
324/754	1675	324/755.03	2
324/771	90	324/762.02	3
324/756	53	324/750.19	3
324/766	95	324/754.03	2
324/765	1552	324/754.16	2
324/158.1	1119	324/754.27	1
324/772	300	324/756.01	1
324/757	142	324/756.05	4
324/158.1	1119	324/759.03	5
324/768	75	324/762.03	1
324/158.1	1119	324/762.07	1
324/750	130	324/762.09	1
		324/750.02	3
324/158.1	1119	324/750.06	2
324/752	156	324/750.14	9
324/757	142	324/750.17	1
324/753	72	324/750.3	1
324/761	338	324/754.07	13
324/766	95	324/754.2	1
324/158.1	1119	324/754.21	6
324/758	419	324/755.05	6
324/754	1675	324/756.07	16
324/158.1	1119	324/758.04	2
		324/759.02	3

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
		324/762.09	7
324/762	181	324/755.01	1
324/758	419	324/756.02	1
324/751	215	324/762.01	1
324/769	169	324/762.05	2
324/158.1	1119	324/763.02	1
324/765	1552	324/750.03	5
324/764	20	324/754.02	1
324/752	156	324/754.27	1
324/758	419	324/750.23	3
324/765	1552	324/754.07	3
324/758	419	324/754.08	1
324/755	479	324/754.18	1
324/770	234	324/760.01	39
324/769	169	324/762.09	15
324/767	184	324/750.05	1
324/766	95	324/754.23	1
324/765	1552	324/754.31	1
324/761	338	324/755.1	1
324/754	1675	324/756.03	58
324/765	1552	324/757.03	3
324/769	169	324/762.08	9
324/761	338	324/754.03	2
324/755	479	324/754.12	1
324/754	1675	324/755.11	22
324/760	449	324/756.06	1
324/765	1552	324/758.01	2
		324/762.05	7
324/754	1675	324/750.24	1
		324/754.01	3
324/763	517	324/754.29	1
324/765	1552	324/755.01	1
324/772	300	324/765.01	19
324/761	338	324/750.11	3
324/750	130	324/754.22	1
324/761	338	324/762.02	1
324/765	1552	324/764.01	7
		324/750.15	1
		324/754.01	2
324/762	181	324/754.07	1
324/761	338	324/755.01	2
324/765	1552	324/762.06	5
324/772	300	324/546	2

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DISPOSITION CLASSIFICATION(S) OF PATENTS
FROM ABOLISHED SUBCLASSES REPORT

Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/767	184	340/645	1
324/158.1	1119	356/630	1
324/763	517	361/728	1
324/760	449	703/14	1
324/772	300	324/418	1
324/750	130	324/537	1
		73/25.01	1
324/158.1	1119	324/555	1
324/771	90	379/24	1
324/772	300	73/514.39	1
324/762	181	324/601	1
324/754	1675	324/719	1
324/772	300	324/258	1
324/158.1	1119	73/1.79	1
324/771	90	324/429	1
324/765	1552	438/18	1
		324/678	1
324/760	449	257/48	1
324/765	1552	324/671	1
324/772	300	324/502	1
		324/547	1
		73/1.72	1
324/158.1	1119	324/537	11
324/763	517	438/110	2
324/769	169	323/266	1
324/772	300	324/378	1
		361/20	1
324/763	517	324/503	1
324/772	300	318/400.01	1
324/158.1	1119	323/273	1
324/758	419	382/151	1
324/763	517	324/754.11	1
324/752	156	324/754.06	2
324/158.1	1119	324/754.1	3
324/765	1552	327/543	1
324/158.1	1119	455/302	1
324/772	300	324/389	1
324/754	1675	335/5	1
324/750	130	356/237.5	1
324/158.1	1119	307/125	1
324/758	419	324/750.14	2
324/760	449	324/750.19	1
		324/750.22	1

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Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/755	479	324/750.27	2
324/768	75	324/754.03	1
324/754	1675	324/754.09	6
324/758	419	324/754.1	1
324/754	1675	324/754.23	3
324/158.1	1119	324/755.08	2
324/757	142	324/756.02	6
324/762	181	324/756.03	22
324/158.1	1119	324/756.04	6
324/754	1675	324/762.04	4
324/763	517	324/762.05	5
324/751	215	324/750.23	1
324/762	181	324/750.27	2
324/770	234	324/750.3	14
324/760	449	324/750.3	2
324/772	300	324/750.3	1
324/762	181	324/754.08	1
324/758	419	324/754.13	1
324/761	338	324/754.15	4
324/158.1	1119	324/755.02	4
324/765	1552	324/755.09	3
324/758	419	324/755.11	1
		324/756.03	10
324/761	338	324/757.02	1
324/763	517	324/759.03	1
324/767	184	324/760.01	1
324/756	53	324/750.11	1
324/751	215	324/750.16	3
324/755	479	324/750.23	4
324/756	53	324/750.23	1
324/754	1675	324/754.04	8
324/767	184	324/754.07	1
324/751	215	324/754.09	1
324/158.1	1119	324/754.13	1
324/768	75	324/754.14	1
324/158.1	1119	324/754.15	2
		324/754.22	6
324/753	72	324/754.23	28
324/158.1	1119	324/757.01	19
324/770	234	324/758.02	1
324/771	90	324/750.14	1
324/158.1	1119	324/750.16	4
324/771	90	324/750.3	5

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DISPOSITION CLASSIFICATION(S) OF PATENTS
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Source Classification	Number of ORs	New Classification	Number of ORs
324/762	181	324/754.12	1
324/770	234	324/754.22	6
324/750	130	324/754.27	8
324/766	95	324/754.28	1
324/753	72	324/755.01	1
324/765	1552	324/755.07	1
324/768	75	324/762.08	49
324/767	184	324/762.08	7
324/750	130	324/750.03	1
324/755	479	324/750.08	1
324/765	1552	324/750.22	6
324/751	215	324/750.25	1
324/761	338	324/754.09	1
		324/754.1	2
324/765	1552	324/754.2	6
324/767	184	324/754.26	1
324/754	1675	324/755.05	46
		324/755.11	20
324/760	449	324/758.01	1
324/158.1	1119	324/759.01	3
324/754	1675	324/762.03	1
324/762	181	324/750.05	1
324/754	1675	324/750.08	8
324/756	53	324/750.09	1
324/754	1675	324/750.24	13
		324/754.12	5
324/767	184	324/754.21	3
324/753	72	324/754.21	2
324/760	449	324/755.06	1
324/772	300	324/756.02	1
324/771	90	324/756.02	1
324/758	419	324/756.04	3
324/759	15	324/759.01	1
324/752	156	324/762.05	2
324/158.1	1119	324/762.06	2
324/761	338	324/750.01	2
324/755	479	324/750.13	1
324/772	300	324/750.25	2
324/765	1552	324/754.11	5
324/158.1	1119	324/754.19	3
324/757	142	324/756.03	5
324/765	1552	324/756.04	3
324/770	234	324/756.07	2

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DISPOSITION CLASSIFICATION(S) OF PATENTS
FROM ABOLISHED SUBCLASSES REPORT

Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
324/158.1	1119	324/758.01	1
324/769	169	324/762.01	5
324/753	72	324/750.02	1
324/757	142	324/750.03	1
324/762	181	324/754.07	13
324/755	479	324/754.11	1
		324/754.2	2
324/757	142	324/755.1	2
324/765	1552	324/756.02	45
324/770	234	324/756.02	2
324/763	517	324/757.04	1
		324/755.03	1
324/158.1	1119	324/757.03	12
324/758	419	324/750.02	2
324/761	338	324/750.02	1
324/754	1675	324/754.05	2
324/756	53	324/754.1	2
324/762	181	324/755.05	1
324/755	479	324/750.02	1
		324/750.09	1
324/761	338	324/750.24	1
324/754	1675	324/755.02	3
324/158.1	1119	324/755.03	1
324/754	1675	324/755.07	8
324/158.1	1119	324/750.16	8
324/769	169	324/750.3	1
324/770	234	324/754.03	1
324/765	1552	324/754.19	1
		324/756.03	1
324/763	517	324/764.01	2
324/750	130	324/750.23	1
324/755	479	324/756.03	1
324/158.1	1119	324/764.01	8
		324/750.23	2
		324/754.23	3
324/754	1675	324/755.03	3
324/158.1	1119	324/750.09	1
324/761	338	324/750.19	1
324/765	1552	324/756.04	1
324/760	449	324/762.05	1
324/158.1	1119	324/756.05	4
324/767	184	257/461	1
324/158.1	1119	324/123 R	1

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DISPOSITION CLASSIFICATION(S) OF PATENTS
FROM ABOLISHED SUBCLASSES REPORT

Generated by Data Control Division

Source Classification	Number of ORs	New Classification	Number of ORs
		323/290	1
		708/625	1
324/766	95	250/393	1
324/772	300	73/862.193	1
324/158.1	1119	324/71.3	1
		324/105	1
324/771	90	324/525	1
324/765	1552	326/102	1
324/771	90	455/127.2	1
324/772	300	324/108	1
		324/117 R	1
324/765	1552	324/550	1
324/756	53	324/546	1
324/772	300	29/732	1
324/158.1	1119	700/115	1
		377/20	1
324/768	75	361/104	1
324/753	72	324/537	1
324/750	130	324/76.19	1
324/765	1552	324/76.11	5
324/769	169	324/132	1
324/158.1	1119	324/119	1
		324/115	2
		716/126	1
		257/48	2
		324/601	1
324/765	1552	324/754.14	3
324/158.1	1119	324/750.23	5
		324/754.22	1
		324/756.01	10
324/769	169	703/14	1
324/158.1	1119	340/870.02	1
324/760	449	324/142	1
324/751	215	850/56	1

C. CHANGES TO THE USPC-TO-IPC CONCORDANCE

USPC		IPC	
Class	Subclass	Subclass	Notation
324	750.01-750.04	G01R	31/00
	750.05-750.11	G01R	31/10
	750.12	G01R	31/308
	750.13	G01R	31/00
	750.14	G01R	31/10
	750.15	G01R	31/36
	750.16	G01R	31/00
	750.17	G01R	31/312
	750.18	G01R	31/20
	750.19-750.21	G01R	31/00
	750.22	G01R	31/01
	750.23	G01R	31/308
	750.24	G01R	31/20
	750.25	G01R	31/20
	750.26	G01R	31/00
	750.27	G01R	31/00
	750.28	G01R	31/10
	750.29	G01R	31/00
	750.3	G01R	31/3187
	754.01-754.16	G01R	31/20
	754.17	G01R	31/308
	754.18- 754.2	G01R	31/00
	754.21	G01R	31/302
	754.22	G01R	31/305
	754.23	G01R	31/308
	754.24-754.26	G01R	31/308
	754.27	G01R	31/302
	754.28	G01R	31/312
	754.29-754.31	G01R	31/302
	755.01-755.11	G01R	1/067
		G01R	31/00
	756.01-756.07	G01R	31/00
	757.01-757.05	G01R	31/20
	758.01-758.05	G01R	31/20
	759.01-759.03	G01R	31/00
	760.01-760.02	G01R	31/26
	761.01	G01R	31/26
	762.01-762.1	G01R	31/26
		G01R	31/02
	763.01- 763.02	G01R	31/28
			31/304
			31/306
			31/309
	764.01	G01R	31/40
	765.01	G01R	31/34

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D. CHANGES TO THE DEFINITIONS

CLASS 33 - GEOMETRICAL INSTRUMENTS

Definition Modified

Subclass 561: Under SEE OR SEARCH CLASS

Delete:

The reference to Class 324

Insert:

324, Electricity: Measuring and Testing, subclasses 754.01 through 755.11 for electrical testing using probe techniques.

D. CHANGES TO THE DEFINITIONS

CLASS 73 - MEASURING AND TESTING

Definitions Modified

Subclass 114.01: Under SEE OR SEARCH CLASS

Delete:

The reference to Class 324

Insert:

324, Electricity Measuring and Testing, subclasses 378 through 402 for subject matter relating to the testing of electrical systems and devices for engine ignition systems and subclass 765.01 for measuring or testing an electric motor or generator for faults.

D. CHANGES TO THE DEFINITIONS

CLASS 257 – ACTIVE SOLID-STATE DEVICES (E.G., TRANSISTORS, SOLID-STATE DIODES)

Definitions Modified

Class Definition: SECTION IV – REFERENCES TO OTHER CLASSES

Delete:

The reference to Class 324

Insert:

324, Electricity: Measuring and Testing, subclasses 762.01 through 762.1 for testing semiconductor devices, SCR and transistor testing and subclasses 244+ for magnetometers many of which employ active solid-state devices, e.g., subclasses 248 (thin film), 251 (Hall plate) and 252 (semiconductor type solid-state or magneto resistive). (Class employing active solid-state devices in electronic circuits. See Lines With Other Classes and Within This Class, A, above).

D. CHANGES TO THE DEFINITIONS

CLASS 310 - ELECTRICAL GENERATOR OR MOTOR STRUCTURE

Definitions Modified

Subclass 12.19: Under SEE OR SEARCH CLASS

Delete:

The reference to Class 324

Insert:

324, Electricity: Measuring and Testing, subclass 765.01 for the testing of an assembled motor or generator not elsewhere classifiable.

D. CHANGES TO THE DEFINITIONS

CLASS 324 - ELECTRICITY: MEASURING AND TESTING

Definitions Abolished

Subclasses

158.1, 750-772

Definitions Modified

Subclass 73.1: Under SEE OR SEARCH THIS CLASS, SUBCLASS

Delete:

The reference to Class 754+

Insert:

754.01-755.11, for test probe techniques.

Subclass 261: Under SEE OR SEARCH THIS CLASS, SUBCLASS

Delete:

The reference to Class 158.1

Insert:

756.01-756.07, for Support for device under test or test structure in electrical testing generally.

D. CHANGES TO THE DEFINITIONS

Subclass 262: Under SEE OR SEARCH THIS CLASS, SUBCLASS

Delete:

The reference to Class 158

Insert:

756.01-756.07, for Support for device under test or test structure in electrical testing generally.

Subclass 545: Under SEE OR SEARCH THIS CLASS, SUBCLASS

Delete:

The reference to Class 772

Insert:

765.01, for motor generator testing.

Subclass 719: Under SEE OR SEARCH THIS CLASS, SUBCLASS

Delete:

The reference to Class 765

Insert:

762.01 through 762.1, for miscellaneous electrical transistor testing.

D. CHANGES TO THE DEFINITIONS

Definition Established

750.01 Measurement or control of test condition:
This subclass is indented under subclass 537. Subject matter wherein a condition (e.g., temperature, applied voltage, pressure) of the device under test, or of the testing equipment, is set up prior to or maintained during the test.

750.02 Calibration of test equipment:
This subclass is indented under subclass 750.01. Subject matter wherein a precondition of the test equipment is measured or adjusted to meet a certain standard.

750.03 Thermal preconditioning or temperature control:
This subclass is indented under subclass 750.01. Subject matter including means to set or maintain the temperature of the device under test, or the temperature of the testing equipment, at a desired level before or during the test.

750.04 Thermal matching of guidance member:
This subclass is indented under subclass 750.03. Subject matter wherein means to guide or align contacts on the testing device with respect to contacts on the device under test is heated or cooled to match the thermal impedance of the device under test.

750.05 Burn-in:
This subclass is indented under subclass 750.03. Subject matter including means for raising the temperature of the device under test for a specified period of time under an electrical power stress.

750.06 With temperature sensing:
This subclass is indented under subclass 750.05. Subject matter for measuring the temperature of the device under test during burn-in.

750.07 With feedback control:
This subclass is indented under subclass 750.06. Subject matter for automatically varying or regulating the temperature of the device under test by sensing deviations of its temperature from a desired value.

750.08 By fluid:
This subclass is indented under subclass 750.03. Subject matter wherein the temperature of the device under test or of the testing equipment is varied or maintained by the circulation of a heating or cooling liquid or gas.

750.09 By heat sink:
This subclass is indented under subclass 750.03. Subject matter wherein the temperature of the device under test is varied or maintained by the conduction of heat from the DUT to a heat absorbing means.

750.1 With biasing means:
This subclass is indented under subclass 750.09. Subject matter comprising means to urge the device under test into contact with the heat conducting or absorbing means.

D. CHANGES TO THE DEFINITIONS

750.11 Thermoelectric:
This subclass is indented under subclass 750.03. Subject matter wherein the temperature preconditioning or control means includes means that directly converts electric energy to heat.

750.12 Electromagnetic:
This subclass is indented under subclass 750.03. Subject matter wherein the temperature preconditioning or control means includes means for raising or maintaining the temperature of the device under test or the testing equipment by electromagnetic radiation.

750.13 Of test device transporting means:
This subclass is indented under subclass 750.03. Subject matter wherein a means for moving the test device to a testing station includes means to set or maintain the temperature of the device to be tested.

750.14 Environmental control:
This subclass is indented under subclass 537. Subject matter comprising means to change or maintain a characteristic, of the surroundings of the test, e.g., humidity, vibration.

750.15 With identification on device under test (DUT):
This subclass is indented under subclass 537. Subject matter wherein a device under test (DUT) has unique marks or codes that can be read to determine the identity of the DUT.

(1) Note. This subclass includes a DUT having identifying marks usable in determining faults or defects in electric components or elements. Identification apparatus and processes of general utility involving bar code are classified elsewhere.

(2) Note. Automated analysis of an image or recognition of a pattern of machine readable, human language symbols are constructed entirely of spaced-apart, substantially parallel bars, lines or strokes is classifiable elsewhere.

750.16 Relative positioning or alignment of device under test and test structure:
This subclass is indented under subclass 537. Subject matter comprising means to position, or to assist in the position of, a testing structure, e.g., a test head, relative to a device under test, or vice versa.

(1) Note. Subject matter of this subclass type includes alignment means to assist in the relative positioning by giving an indication of the amount of deviation of the two parts from a desired positional relationship.

750.17 By capacitive means:
This subclass is indented under subclass 750.16. Subject matter including means for sensing the capacitance between the device under test and the test structure.

750.18 By information on device under test:
This subclass is indented under subclass 750.16. Subject matter including alignment information on the device under test or test structure.

D. CHANGES TO THE DEFINITIONS

750.19 Adjustable support for device under test:
This subclass is indented under subclass 750.16. Subject matter wherein a dimension of the support for the device under test is variable.

750.2 Vacuum support:
This subclass is indented under subclass 750.19. Subject matter wherein the device under test is affixed to the support by sub-atmospheric pressure.

750.21 Magnetic support:
This subclass is indented under subclass 750.19. Subject matter wherein the device under test is affixed to the support by a magnetic attraction.

750.22 Testing device mounted for multi-directional movement:
This subclass is indented under subclass 750.16. Subject matter wherein the support for the testing permit movements relative to the device under test in two or more intersecting directions.

750.23 Using optical means:
This subclass is indented under subclass 750.16. Subject matter including means for optically sensing the alignment of the device under test and the test structure.

750.24 By electrical contact means:
This subclass is indented under subclass 750.16. Subject matter including electrical contacts on the device under test and on the test structure which are mutually engageable to indicate alignment thereof.

750.25 By mechanical means:
This subclass is indented under subclass 750.16. Subject matter including physical structures on the device under test and on the test structure which cooperate to align the two.

750.26 Shielding or casing of device under test or of test structure:
This subclass is indented under subclass 537. Subject matter comprising means surrounding the device under test or the test structure to prevent, or reduce the influence of, external effects, e.g., air current, electromagnetic fields.

750.27 EMI interference:
This subclass is indented under subclass 750.26. Subject matter wherein the external effect is electromagnetic radiation.

750.28 Temperature effect:
This subclass is indented under subclass 750.26. Subject matter wherein the external effect is heat or cold.

750.29 Mechanical effect:
This subclass is indented under subclass 750.26. Subject matter wherein the external effect is mechanical stress, shock, or vibration.

750.3 Built-in test circuit:
This subclass is indented under subclass 537. Subject matter wherein the means for testing is a circuit incorporated into the component under test.

D. CHANGES TO THE DEFINITIONS

754.01 Test probe techniques:
This subclass is indented under subclass 537. Subject matter comprising non-quantitative tests using a test structure (probe) that transmits a test signal to the device under test which is returned to and detected by the testing structure.

754.02 Hand-held:
This subclass is indented under subclass 754.01. Subject matter wherein the test structure is a hand held probe.

754.03 Contact probe:
This subclass is indented under subclass 754.01. Subject matter wherein the test signal is transmitted to and received from the device under test by direct ohmic contact between the device under test and the testing structure.

754.04 Liquid state:
This subclass is indented under subclass 754.03. Subject matter wherein the direct contact is made through a conductive fluid.

754.05 Kelvin probe:
This subclass is indented under subclass 754.03. Subject matter wherein the test structure includes two separate contact point, one for current and one for voltage.

754.06 Waveguide probe:
This subclass is indented under subclass 754.03. Subject matter wherein the contacts are mounted on a waveguide or transmission line.

754.07 Probe or probe card with built-in circuit element:
This subclass is indented under subclass 754.03. Subject matter wherein the contact probe or its immediate support includes an electronic circuit component.

(1) Note. Electric circuit elements of this subclass type include, for example, a circuit trace, a lumped impedance, active component or a complete microprocessor.

754.08 In or on support for device under test:
This subclass is indented under subclass 754.03. Subject matter wherein the transmitter/receiver contacts are built into or on means for holding the device under test.

754.09 Carrier feature:
This subclass is indented under subclass 754.08. Subject matter wherein a support for the device under test includes a built-in testing circuit.

754.1 Probe contact confirmation:
This subclass is indented under subclass 754.03. Subject matter including a feature to enable determination whether proper probe contact has been made.

754.11 Probe contact enhancement or compensation:
This subclass is indented under subclass 754.03. Subject matter including a feature for aiding the probe to make proper contact.

D. CHANGES TO THE DEFINITIONS

(1) Note. This subclass includes means such as to improve or correct for getting a proper contact between the probe and the device under test.

754.12 Biasing means:
This subclass is indented under subclass 754.03. Subject matter including means to urge a contact on the testing structure into engagement with a contact on the device under test.

754.13 Mechanical:
This subclass is indented under subclass 754.12. Subject matter wherein the biasing means includes a mechanism to urge the contacts into engagement.

754.14 Spring:
This subclass is indented under subclass 754.12. Subject matter including a resilient member to urge the contacts into engagement.

754.15 Fluid pressure:
This subclass is indented under subclass 754.12. Subject matter wherein the contacts are urged into engagement by gas or liquid pressure.

754.16 Chamber or bladder:
This subclass is indented under subclass 754.15. Subject matter wherein the gas or liquid pressure is created or maintained by a resilient gas or liquid storage device.

754.17 Magnetic means:
This subclass is indented under subclass 754.12. Subject matter wherein the contacts are urged into engagement by magnetic force.

754.18 With interpose:
This subclass is indented under subclass 754.03. Subject matter wherein the signal is transmitted to and received from the device under test through a substrate or layer having a plurality of electrical inter-connectors.

754.19 With recording of test result:
This subclass is indented under subclass 754.03. Subject matter comprising means for capturing and storing the results of the test.

754.2 Penetrative:
This subclass is indented under subclass 754.03. Subject matter wherein the contact probe includes means to scrape away or pierce an oxidation layer on the contact point of the device under test.

754.21 Non-contact probe:
This subclass is indented under subclass 754.01. Subject matter wherein the test signal is transmitted to and received from the device under test by some means other than direct ohmic contact between the device under test and the testing structure.

754.22 Electron beam:
This subclass is indented under subclass 754.21. Subject matter wherein the test signal is transmitted to and from the device under test by a beam of electrons.

D. CHANGES TO THE DEFINITIONS

754.23 Optical beam:
This subclass is indented under subclass 754.21. Subject matter wherein the test signal is transmitted to and from the device under test by a beam of light, e.g., a laser beam.

754.24 With plasma probe:
This subclass is indented under subclass 754.21. Subject matter wherein the test signal is transmitted to and from the device under test by utilizing plasma gas directed across the surface of the device under test.

754.25 Ultrasonic:
This subclass is indented under subclass 754.21. Subject matter wherein the test signal is transmitted to and from the device under test by a beam of sound waves having a frequency above the audible range.

754.26 Tunnel current probe:
This subclass is indented under subclass 754.21. Subject matter wherein the test signal is transmitted to and from the device under test by tunnel current flowing therebetween.

754.27 Electrical field:
This subclass is indented under subclass 754.21. Subject matter wherein the test signal is transmitted to and from the device under test by an electric field.

754.28 Capacitive coupling:
This subclass is indented under subclass 754.27. Subject matter wherein the signal is transmitted between an electric field emitting probe and the device under test by mutual electrostatic induction.

754.29 Magnetic field:
This subclass is indented under subclass 754.21. Subject matter wherein the test signal is transmitted to and from the device under test by a magnetic field.

754.3 Intermolecular:
This subclass is indented under subclass 754.21. Subject matter wherein the test signal is transmitted to and from the device under test by intermolecular or Coulomb forces.

754.31 Radio wave:
This subclass is indented under subclass 754.21. Subject matter wherein the test signal is transmitted to and from the device under test by a modulated electromagnetic carrier wave.

755.01 Probe structure:
This subclass is indented under subclass 537. Subject matter comprising means to transmit a test signal to a device under test and to detect a returned signal.

755.02 Coaxial:
This subclass is indented under subclass 755.01. Subject matter wherein the probe consists of two electrical conductors, one inside the other and separated by a dielectric material.

D. CHANGES TO THE DEFINITIONS

755.03 Rigid:
This subclass is indented under subclass 755.01. Subject matter wherein the probe is inflexible.

755.04 Force absorption:
This subclass is indented under subclass 755.01. Subject matter comprising means to absorb forces directed longitudinally of the probe.

755.05 Spring:
This subclass is indented under subclass 755.04. Subject matter wherein the force is absorbed by a flexible member against which the probe acts.

755.06 Buckling:
This subclass is indented under subclass 755.04. Subject matter wherein the longitudinal force is absorbed by lateral deflection of a flexible probe.

755.07 Cantilever:
This subclass is indented under subclass 755.01. Subject matter comprising flexible probes which are supported generally perpendicularly with respect to the direction of their contact with the device under test.

755.08 Elastomeric:
This subclass is indented under subclass 755.01. Subject matter comprising probes made of a resilient material having suitable compressive and adhesive characteristic and containing conductive particles which produce z- axis conduction when pressed in a z-axis direction.

755.09 Membrane:
This subclass is indented under subclass 755.01. Subject matter comprising probes characterized by a flexible or semi-flexible substrate with traces and contacting portions supported together to contact the device under test.

755.1 Dendritic structure:
This subclass is indented under subclass 755.01. Subject matter wherein the contact surface of the probe includes minute finger-like or particle-like protrusions.

755.11 Elongated pin or probe:
This subclass is indented under subclass 755.01. Subject matter wherein the probe or probing structure has a slender, rod-like shape.

756.01 Support for device under test or test structure:
This subclass is indented under subclass 537. Subject comprising means to support the device under test or to support a test structure.

756.02 DUT socket or carrier:
This subclass is indented under subclass 756.01. Subject matter wherein the supporting device is socket or carrier retaining the device under test and coupled to the test structure for making electrical contact with the device under test.

D. CHANGES TO THE DEFINITIONS

756.03 Probe card:
This subclass is indented under subclass 756.01. Subject matter wherein the support is a holding device for holding plurality of probe elements and for providing a desired pressure of the probe elements against the device under test.

756.04 Pin fixture:
This subclass is indented under subclass 756.01. Subject matter for attaching a probe to a probe card or other support.

756.05 With electrical connectors:
This subclass is indented under subclass 756.01. Subject matter including means to electrically connect a probe to other electrical circuitry.

756.06 With impedance matching:
This subclass is indented under subclass 756.01. Subject matter wherein the support includes circuitry for matching or regulating the impedance characteristic between the test structure and the device under test.

756.07 Board or plate:
This subclass is indented under subclass 756.01. Subject matter wherein the support is a planar member.

757.01 Transporting or conveying the device under test to the testing station:
This subclass is indented under subclass 537. Subject matter for moving the device to be tested to the testing structure.

(1) Note. The transporting or conveying may include passage through an intermediate station, such as for indexing.

SEE OR SEARCH THIS CLASS, SUBCLASS

750.13, for test device transporting or conveying means having means to set or maintain the temperature of the device to be tested.

757.02 Printed circuit board:
This subclass is indented under subclass 757.01. Subject matter wherein the device to be tested is an essentially two-sided dielectric member on at least one side of which circuit elements are mounted or deposited.

SEE OR SEARCH THIS CLASS, SUBCLASS

763.01, for transporting or conveying a printed circuit board combined with testing of the printed circuit board.

757.03 Wafer:
This subclass is indented under subclass 757.01. Subject matter wherein the device to be tested consists of a thin slice of semiconductor material.

D. CHANGES TO THE DEFINITIONS

SEE OR SEARCH THIS CLASS, SUBCLASS

762.05, for transporting combined with testing of semiconductor wafers.

757.04 Packaged IC or unpackaged die or dice:
This subclass is indented under subclass 757.01. Subject matter wherein the device to be tested is an integrated circuit contained in a protective means and provided with electrical access means.

757.05 Multiple chip module:
This subclass is indented under subclass 757.01. Subject matter wherein the device to be tested is a specialized electronic package where multiple integrated circuits (ICs), semiconductor dies or other modules are packaged in such a way as to facilitate their use as a single IC.

758.01 Cleaning probe or device under test:
This subclass is indented under subclass 537. Subject matter wherein the further processing includes removing undesired material from the test probe or the device under test.

758.02 By laser ablation:
This subclass is indented under subclass 758.01. Subject matter wherein the probe is cleaned by burning off the undesired material by laser radiation.

758.03 By blowing air:
This subclass is indented under subclass 758.01. Subject matter wherein the probe is cleaned by a stream of air flowing over it.

758.04 By scraping:
This subclass is indented under subclass 758.01. Subject matter wherein the probe is cleaned mechanical abrasion.

758.05 By chemical means:
This subclass is indented under subclass 758.01. Subject matter wherein the probe is cleaned by the action of a chemical applied to the undesired material.

759.01 After-test activity:
This subclass is indented under subclass 537. Subject matter wherein the device under test or the testing equipment undergoes further processing after the test tested.

759.02 Marking tested objects:
This subclass is indented under subclass 759.01. Subject matter wherein the further processing includes marking the tested device to indicate its passed/failed status.

759.03 Sorting tested objects:
This subclass is indented under subclass 759.01. Subject matter wherein the further processing includes the separation of passed tested devices from failed ones.

760.01 Test of liquid crystal device:
This subclass is indented under subclass 537. Subject matter including test of a device whose reflectance or transmittance properties change when an electric field is applied.

D. CHANGES TO THE DEFINITIONS

(1) Note. This subclass includes testing singular or plural LCD elements for electrical defects or faults.

(2) Note. Subject matter related to optical properties of an LCD array to produce an image is classified elsewhere.

(3) Note. Subject matter related to measurement optical properties of LCD elements or systems is classified elsewhere.

(4) Note. Subject matter related to LCD elements and systems is classified elsewhere.

SEE OR SEARCH CLASS

345, Computer Graphics Processing and Selective Visual Display Systems, subclass 50 for liquid crystal elements.

349, Liquid Crystal Cells, Elements and Systems, appropriate subclasses for utilizing a liquid crystal device in general.

356, Optics: Measuring and Testing, appropriate subclasses for LCD fault detection and testing, per se.

760.02 Thin film transistor type (TFT):
This subclass is indented under subclass 760.01. Subject matter wherein each pixel of an LCD includes a switching transistor.

761.01 Test of solar cell:
This subclass is indented under subclass 537. Subject matter including test of a device that generates electricity when exposed to sun light or activated by heat from the sun.

762.01 Test of semiconductor device:
This subclass is indented under subclass 537. Subject matter including a determination of faults in an electronic circuit or circuit component made of a material which is a solid or liquid conductor with resistivity between that of metals and that of insulators.

SEE OR SEARCH CLASS

438, Semiconductor Device Manufacturing: Process, subclasses 17+ for methods of making semiconductor electrical devices combined with measurement of an electrical condition.

762.02 Packaged integrated circuits:
This subclass is indented under subclass 762.01. Subject matter wherein the semiconductor device is contained in a protective means and provided with electrical access means.

762.03 Integrated circuit die:
This subclass is indented under subclass 762.01. Subject matter wherein the semiconductor device is one of several complete circuits formed on a slice of semiconductor material.

D. CHANGES TO THE DEFINITIONS

762.04 TAB carrier:
This subclass is indented under subclass 762.03. Subject matter wherein the die is carried on a tape, such as a TAB (tape Automated Bonding) carrier.

762.05 Semiconductor wafer:
This subclass is indented under subclass 762.01. Subject matter wherein the semiconductor device is a thin slice of semiconductive material.

762.06 Multiple chip module:
This subclass is indented under subclass 762.01. Subject matter wherein the device to be tested is a specialized electronic package where multiple integrated circuits (ICs), semiconductor dies or other modules are packaged in such a way as to facilitate their use as a single IC.

762.07 Diode:
This subclass is indented under subclass 762.01. Subject matter wherein the semiconductor device is comprised of two-electrodes (anode and cathode and a single junction (P-N).

762.08 Bipolar transistor:
This subclass is indented under subclass 762.01. Subject matter wherein the semiconductor device has at least three electrodes (emitter, base, and collector), two potential barriers and a controlled current flow of both majority and minority carriers (holes and electrons).

762.09 Field effect transistor:
This subclass is indented under subclass 762.01. Subject matter wherein the semiconductor device is a unipolar transistor in which current carriers are injected at a source terminal and pass to a drain terminal through a channel of semiconductor material whose conductivity depends largely on an electrical field applied to the semiconductor from a control electrode (gate).

762.1 With barrier layer:
This subclass is indented under subclass 762.01. Subject matter wherein the individual circuit component having a region in which the mobile carrier charge density is insufficient to neutralize the net fixed charge density of donors and acceptors.

763.01 Printed circuit board:
This subclass is indented under subclass 537. Subject matter in which the tested component consists of an essentially two-sided dielectric member on at least one side of which circuit elements are mounted or deposited.

SEE OR SEARCH THIS CLASS, SUBCLASS

750.13, for transporting or conveying a printed circuit to a test structure wherein the transporting or conveying means sets or maintains the temperature of the device to be tested.

757.02, for means to transport or convey a printed circuit to the testing structure.

763.02 Both sides:
This subclass is indented under subclass 763.01. Subject matter comprising printed circuit boards having circuit elements mounted or deposited on opposite sides.

D. CHANGES TO THE DEFINITIONS

764.01 Power supply:
This subclass is indented under subclass 537. Subject matter wherein the electric component tested is a source of electrical power.

(1) Note. Electrical testing of rectifying and inverting power supplies are classified in this subclass while rectifying and inverting power supplies having means which control magnitude or level of the current, voltage, or phase angle are classified elsewhere.

SEE OR SEARCH CLASS

323, Electricity: Power Supply or Regulation Systems, for systems for controlling the current, voltage, or phase angle of electrical power sources.

765.01 Motor or generator fault:
This subclass is indented under subclass 537. Subject matter wherein the electrical component tested is (a) a prime mover rotating electrical machine, or (b) a rotating electrical machine which changes mechanical energy into electrical energy.

(1) Note. This subclass includes the testing of an assembled motor or generator not elsewhere classifiable.

SEE OR SEARCH THIS CLASS, SUBCLASS

545, for armature or rotor.

SEE OR SEARCH CLASS

290, Prime-Mover Dynamo Plants, subclasses 5-44 for electric control of generating plants.

310, Electrical Generator or Motor Structure, for generic structure of electric motors.

318, Electricity: Motive Power Systems, subclass 490 for motor systems having signals, recorders, meters or testing devices.

322, Electricity: Single Generator Systems, subclass 99 for the system including a signal, indicator, recorder or testing.

388, Electricity: Motor Control Systems, for controlling the rate of change of speed of a DC motor.

FOREIGN ART COLLECTIONS

The definitions below correspond to abolished subclasses from which these collections were formed. See the Foreign Art Collection schedule of this class for specific correspondences. [**Note**: The titles and definitions for *indented* art collections include all the details of the one(s) that are hierarchically superior.]

D. CHANGES TO THE DEFINITIONS

FOR 100 System sensing fields adjacent device under test (DUT):
Foreign art collection for detecting faults by sensing an electromagnetic field produced by a device under test.

FOR 101 Using electron beam probe:
Foreign art collection wherein a cathode-ray device is used to sense the fields.

FOR 102 Using light probe:
Foreign art collection wherein light such as a laser beam is used to sense the fields.

FOR 103 Using electro-optic device:
Foreign art collection wherein an electro-optic device such as an electroluminor is used to sense the fields**.**

FOR 104 With probe elements:
Foreign art collection including a feature to enable contact between a device under test (DUT) and a test apparatus.

FOR 105 Internal of or on support for device under test (DUT):
Foreign art collection including a support for the DUT and wherein probe elements are mounted in or on the support.

FOR 106 Contact confirmation:
Foreign art collection including a feature to enable determination whether proper probe contact has been made.

FOR 107 Probe contact enhancement:
Foreign art collection including a feature for aiding the probe to make proper contact.

FOR 108 Probe alignment or positioning:
Foreign art collection including a feature for checking or providing for proper position of probes with respect to contact points on the DUT.

FOR 109 With recording of test results on DUT:
Foreign art collection including means for receiving the results of a test on the (DUT).

FOR 110 With temperature control:
Foreign art collection including means to regulate temperature of the DUT or an apparatus used in testing.

FOR 111 Pin:
Foreign art collection wherein the probe element is a connecting device such as a spring biased rod or a buckling beam (rod).

FOR 112 Cantilever:
Foreign art collection including a probe element set at a first end of a beam wherein the beam has a first end and a second end and the second end is attached to a support.

D. CHANGES TO THE DEFINITIONS

FOR 113 DUT including test circuit:

Foreign art collection wherein a device under test (DUT) has integral elements which can be manipulated to configure the DUT so that tests can be made.

(1) Note. For example, a pad of an IC may, by switching, be connected to enable testing of a part of the IC not normally available for testing.

FOR 114 With identification of DUT:

Foreign art collection wherein a device under test (DUT) has unique marks or codes that can be read to determine the identity of the DUT.

(1) Note. This subclass includes a DUT having identifying marks usable in determining faults or defects in electric components or elements. Identification apparatus and processes of general utility involving bar code are classified elsewhere.

(2) Note. Automated analysis of an image or recognition of a pattern of machine readable, human language symbols are constructed entirely of spaced-apart, substantially parallel bars, lines or strokes is classifiable elsewhere.

FOR 115 Test of semiconductor device:

Foreign art collection including a determination of faults in a material which is a solid or liquid conductor with resistivity between that of metals and that of insulators.

FOR 116 With barrier layer:

Foreign art collection having a region in which the mobile-carrier charge density is insufficient to neutralize the net fixed charge density of donors and acceptors.

FOR 117 Diode:

Foreign art collection including a two electrode (anode and cathode), single junction (PN) semiconductor device used as an active switching element responsive to respective input logic signals to perform the logic function.

FOR 118 Bipolar transistor:

Foreign art collection including a semiconductor device of the type having at least three electrodes (emitter, base, and collector), two potential barriers and having a controlled current flow of both majority and minority carriers (i.e., holes and electrons).

(1) Note. A conventional bipolar transistor has three electrodes which include NPN or PNP type materials; in the NPN type, current flows from a collector terminal to an emitter terminal, and in the PNP type transistor, current flows from an emitter terminal to a collector terminal.

FOR 119 Field effect transistor:

Foreign art collection wherein a logic circuit includes one or more unipolar transistors in which current carriers are injected at a source terminal and pass to a drain terminal through a channel of semiconductor material whose conductivity depends largely on an electrical field applied to the semiconductor from a control electrode (gate).

D. CHANGES TO THE DEFINITIONS

(1) Note. In a unipolar transistor, the source to drain current involves only one type of charge carrier (i.e., holes in a p-type material channel and electrons in an N-type material channel).

FOR 120 Liquid crystal device test:

Foreign art collection including test of a device whose reflectance or transmittance properties change when an electric field is applied.

(1) Note. This subclass includes testing singular or plural LCD elements for electrical defects or faults.

(2) Note. Subject matter related to optical properties of an LCD array to produce an image is classified in elsewhere.

(3) Note. Subject matter related to measurement of optical properties of LCD elements or systems is classified elsewhere.

(4) Note. Subject matter related to LCD elements and systems is classified elsewhere.

FOR 121 Power supply test:

Foreign art collection including test of an electrical power source wherein the electrical power source is obtained by rectifying an AC source or using a DC source.

(1) Note. This subclass includes electrical testing of rectifying and inverting power supplies. Rectifying and inverting power supplies having means which control magnitude or level of the current, voltage, or phase angle are classified in Class 323.

FOR 122 Motor or generator fault tests:

Foreign art collection including fault tests of (a) prime mover rotating electrical machinery; (b) rotating electrical machinery which changes mechanical energy to electrical energy.

(1) Note. This subclass includes the testing of an assembled motor or generator not elsewhere classifiable.

(2) Note. Subject matter for testing just the rotating part of a motor or generator is classified elsewhere in this class. See the search note below.

(3) Note. Subject matter related to prime-mover dynamo plants is classified elsewhere. See the search note below.

(4) Note. Subject matter related to electrical motor or generator structure is classified elsewhere. See the search note below.

(5) Note. Subject matter related to signaling, recording, metering, or testing of systems of supply or control for an electric motor and the electric motor is classified elsewhere. See the search note below.

(6) Note. Subject matter related to indicating, signaling, recording, or testing a single electric energy generator having means to regulate or control the generator output is classified elsewhere. See the search note below.

(7) Note. Subject matter related to systems of acceleration or speed control of DC motors is classified elsewhere. See the search note below.

D. CHANGES TO THE DEFINITIONS

FOR 123 MISCELLANEOUS:

Foreign art collection not provided for in any preceding subclass.

D. CHANGES TO THE DEFINITIONS

CLASS - 349 LIQUID CRYSTAL CELLS, ELEMENTS AND SYSTEMS

Definitions Modified

Class Definition: SECTION III – REFERENCES TO OTHER CLASSES

Delete:

The reference to Class 324

Insert:

324, Electricity: Measuring and Testing, subclasses 760.01 and 760.02 for testing a liquid crystal device for a fault in an individual circuit component.

Subclass 187: Under SEE OR SEARCH CLASS

Delete:

The reference to Class 324

Insert:

324, Electricity: Measuring and Testing, subclasses 760.01 and 760.02 for testing a liquid crystal device for a fault in an individual circuit component.

D. CHANGES TO THE DEFINITIONS

CLASS 702 - DATA PROCESSING: MEASURING, CALIBRATING, OR TESTING

Definitions Modified

Subclass 117: Under SEE OR SEARCH CLASS

Delete:

The reference to Class 324

Insert:

324, Electricity: Measuring and Testing, subclasses 500+ for fault testing in electrical circuits and components, particularly subclasses 537+ for fault testing of individual circuit component or element, subclass 538 for fault testing of electrical connectors, subclasses 762.01 through 762.1 for a fault testing of a semiconductor device, subclass 764.01 for fault testing of a power supply, subclass 726 for transformer testing, subclass 727 for piezoelectric crystal testing, and subclasses 74+ for testing and calibration of electric meters.

D. CHANGES TO THE DEFINITIONS

CLASS 977 – NANOTECHNOLOGY

Definitions Modified

Subclass 852: Under SEE OR SEARCH CLASS

Delete:

The reference to 324

Insert:

324, Electricity: Measuring and Testing, subclasses 72.5, 149, 437, 445, 446, 690, 696, 715, 724, and 754.01 through 755.11 for probe types used in detection processes of electrical properties of a sample.